

EN 55022:2010
EN 55024:2010
EN 61000-3-2:2006 + A1:2009 + A2:2009
EN 61000-3-3:2008
TEST REPORT

For

Yealink (Xiamen) Network Technology Co., Ltd.

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Model: T48G

Report Type: Original Report	Product Type: IP Phone
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GENERAL INFORMATION

Product Description for Equipment under Test (EUT)

The Yealink (Xiamen) Network Technology Co., Ltd. 's product, model number: T48G (the "EUT") in this report is an *IP Phone*, which was measured approximately: 26.5 cm (L) x 22.5 cm (W) x 5.0 cm (H), rated input voltage: DC 5V from adapter or PoE 48V power. The highest operating frequency is 200 MHz.

Adapter 1 information:

Model: OH-1015A0502000U1-VDE

Input: AC 100-240V, 50/60Hz, 350mA

Output: DC 5V, 2A

Adapter 2 information:

Model: NSA15EE-050200

Input: AC 100-240V, 50/60Hz, 0.5A

Output: DC 5V, 2.0A

**All measurement and test data in this report was gathered from production sample serial number: 1308133 (Assigned by BACL, Shenzhen). The EUT supplied by applicable was received on 2013-08-28.*

Objective

This test report is prepared on behalf of Yealink (Xiamen) Network Technology Co., Ltd. in accordance with EN 55022: Information technology equipment-Radio disturbance characteristics-Limits and methods of measurement. EN 55024: Information technology equipment- Immunity characteristics – Limits and methods of measurement. EN 61000-3-2, Limits – Limits for harmonic current emissions (equipment input current up to and including 16 A per phase), and also in accordance with EN 61000-3-3, Limits Section 3; Limitation of voltage fluctuations and flicker in low-voltage supply systems for equipment with rated current <16A.

The objective of the manufacturer is to determine compliance with EN 55022, EN 55024, EN 61000-3-2 and EN 61000-3-3.

Related Submittal(s)/Grant(s)

No related submittal(s).

Test Methodology

All measurements contained in this report were conducted with CISPR 16-1-1:2010, specification for radio disturbance and immunity measuring apparatus and methods P1-1: radio disturbance and immunity measuring apparatus measuring apparatus. CISPR 16-1-4:2012, Specification for radio disturbance and immunity measuring apparatus and methods-Part 1-4: Radio disturbance and immunity measuring apparatus -Ancillary equipment -Radiated disturbances. CISPR 16-2-1:2013, specification for radio disturbance and immunity measuring apparatus and methods P2-1: methods of measurement of disturbance and immunity conducted disturbance measurements. CISPR 16-2-3:2010, specification for radio disturbance and immunity measuring apparatus and methods P2-3 methods of measurement of disturbances and immunity radiated disturbance measurements. CISPR 16-4-2:2011, Specification for radio disturbance and immunity measuring apparatus and methods-Part 4-2: Uncertainties, statistics and limit modeling-Uncertainty in EMC measurements.

All radiated and conducted emissions measurement was performed at Bay Area Compliance Laboratories Corp. (Shenzhen). The radiated testing was performed at an antenna-to-EUT distance of 3 Meters.

Test Facility

The test site used by Bay Area Compliance Laboratories Corp. (Shenzhen) to collect test data is located on the 6/F, the 3rd Phase of WanLi Industrial Building, ShiHua Road, FuTian Free Trade Zone Shenzhen, Guangdong, China.

Test site at Bay Area Compliance Laboratories Corp. (Shenzhen) has been fully described in reports submitted to the Federal Communication Commission (FCC). The details of these reports have been found to be in compliance with the requirements of Section 2.948 of the FCC Rules on December 06, 2010. The facility also complies with the radiated and AC line conducted test site criteria set forth in ANSI C63.4-2009.

The Federal Communications Commission has the reports on file and is listed under FCC Registration No.: 382179. The test site has been approved by the FCC for public use and is listed in the FCC Public Access Link (PAL) database.

SYSTEM TEST CONFIGURATION

Justification

The system was configured for testing in a manufacturer testing fashion.

EUT Exercise Software

No exercise software was used.

Equipment Modifications

No modification was made to the EUT.

Support Equipment List and Details

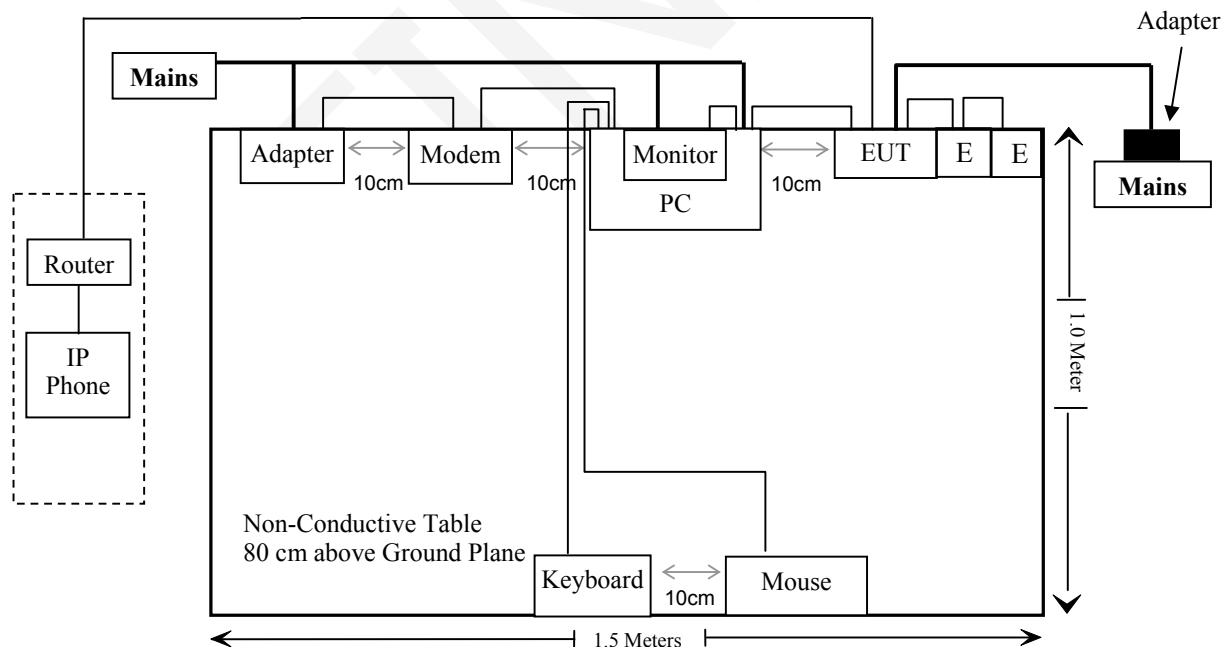
Manufacturer	Description	Model	Serial Number	Remark
DELL	PC	127BPX2	N/A	CE,RE
DELL	PC	Inspiron 660	N/A	EMS, Flicker
DELL	Monitor	E178WFPC	CN-OWY564-64180-7C4-2SQH	CE,RE
DELL	Monitor	E1910Hc	N/A	EMS, Flicker
DELL	Mouse	MOC5UO	G1B0096D	CE,RE
Rapoo	Mouse	N1162	N/A	EMS, Flicker
N/A	Keyboard	KB-US819EB	N/A	CE,RE
LG	Keyboard	ACK-201A	N/A	EMS, Flicker
NETGEAR	POE	FS108P	N/A	/
Sagemcom	Router	N/A	N/A	/
Yealink	IP phone	T48G	N/A	/
ECOM	Modem	5600pbs	N/A	/
NETGEAR	Prosafe 8 port 10/100 switch with 4 port POE	FS108P	272-10168-02	/

External I/O Cable

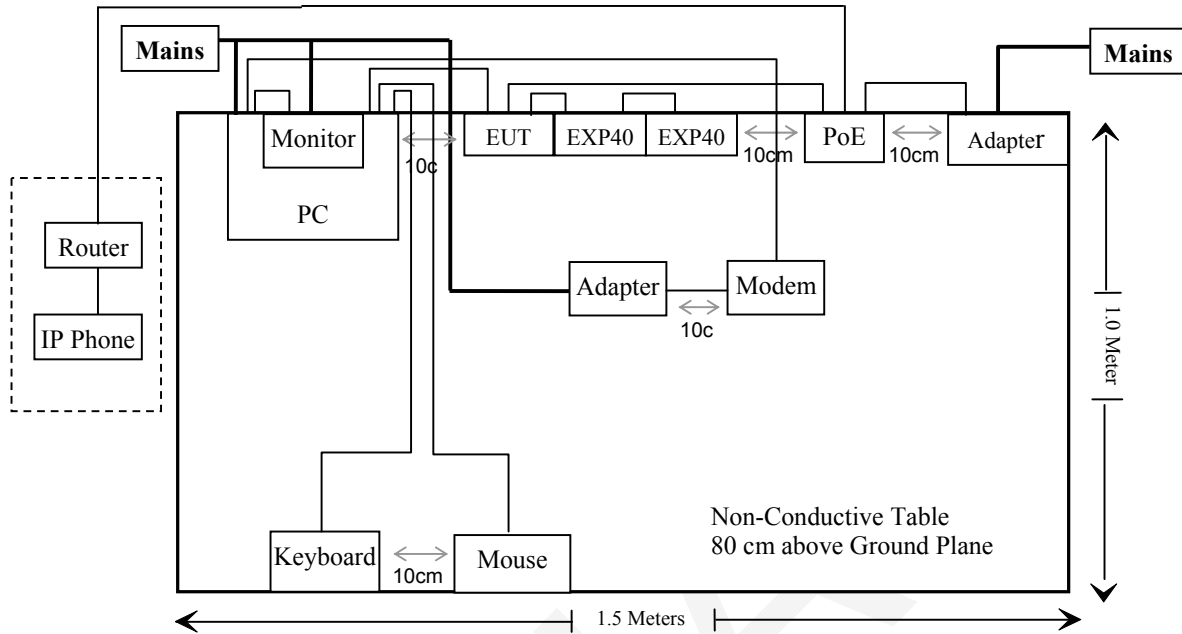
Cable Description	Length (m)	From/Port	To
Shielded Undetachable K/B Cable	1.5	K/B	PC
Shielded Undetachable Mouse Cable	1.5	Mouse	PC
Shielded Undetachable VGA Cable	1.5	Monitor	PC
Unshielded Detachable AC Cable	1.0	Main	Monitor
Unshielded Detachable RS232 Cable	1.5	Modem	PC
Shielded Detachable RJ45 Cable	2.0	EUT	PC
Unshielded Detachable RJ11 Cable	0.2	EUT	EXP40
Unshielded Detachable RJ11 Cable	0.2	EXP40	EXP40
Unshielded Detachable DC Cable	1.5	Adapter	Modem
Unshielded Detachable AC Cable	1.5	Adapter	Main
Unshielded Detachable AC Cable	1.0	Main	PC
Unshielded Detachable RJ45 Cable	1.5	Router	IP Phone
Unshielded Detachable RJ45 Cable	3.0	Router	POE
Shielded Detachable RJ45 Cable	2.0	EUT	POE
Unshielded Detachable DC Cable	0.4	Adapter	POE
Unshielded Detachable DC Cable	1.4	Mains	Adapter

Block Diagram of Test Setup

1) Adapter power supply:

Remark E EXP40

2) PoE power supply:



SUMMARY OF TEST REPORT**EN 55022**

RULE	DESCRIPTION	RESULTS
§ 5.1	Conducted Disturbance at Mains Terminals	Compliance
§ 5.2	Conducted Disturbance at Telecommunication Port	Compliance
§ 6	Radiated Disturbance	Compliance

EN 55024

RULE	DESCRIPTION	RESULTS
§4.2.1	Electrostatic Discharge IEC 61000-4-2	Compliance
§4.2.2	Electrical Fast Transients IEC 61000-4-4	Compliance
§4.2.3.1	Continuous Radiated Disturbance IEC 61000-4-3	Compliance
§4.2.3.2	Continuous Conducted Disturbance IEC 61000-4-6	Compliance
§4.2.4	Power Frequency Magnetic Fields IEC 61000-4-8	Compliance
§4.2.5	Surges IEC 61000-4-5	Compliance
§4.2.6	Voltage Dips And Interruptions, IEC 61000-4-11	Compliance

EN 61000-3-2

Rule	Description	Results
§7	Harmonic Current Emissions	Compliance

EN 61000-3-3

Rule	Description	Results
§5	Voltage Fluctuation and Flicker	Compliance

EN 55022 §5.1-CONDUCTED DISTURBANCE AT MAINS TERMINALS §5.2-CONDUCTED DISTURBANCE AT TELECOMMUNICATION PORT

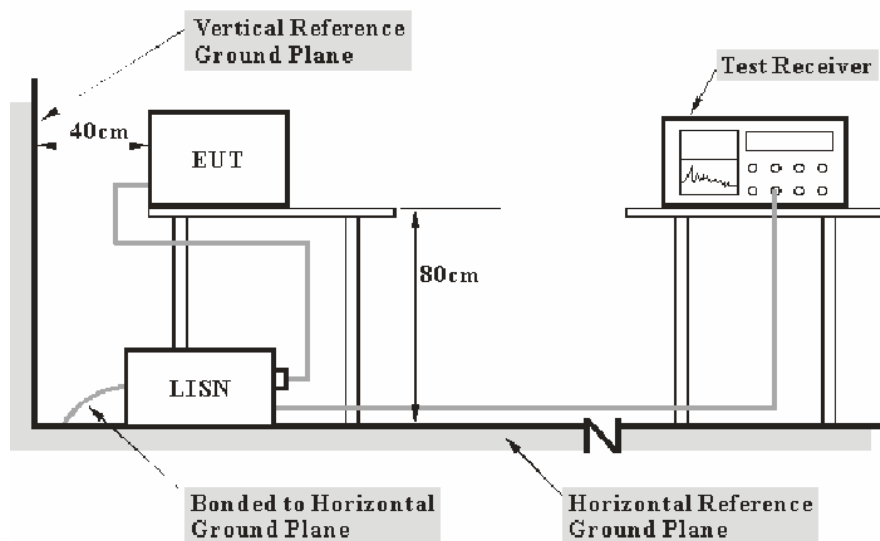
Measurement Uncertainty

Input quantities to be considered for conducted disturbance measurements maybe receiver reading, attenuation of the connection between AMN/ISN and receiver, AMN/ISN voltage division factor, AMN/ISN VDF frequency interpolation and receiver related input quantities, etc.

Based on CISPR 16-4-2:2011, the expended combined standard uncertainty of conducted disturbance test at Bay Area Compliance Laboratories Corp. (Shenzhen) is shown as below. And the uncertainty will not be taken into consideration for the test data recorded in the report

Port	Measurement uncertainty
AC Mains	3.26 dB (k=2, 95% level of confidence)
CAT 3	3.70 dB (k=2, 95% level of confidence)
CAT 5	3.86 dB (k=2, 95% level of confidence)
CAT 6	4.64 dB (k=2, 95% level of confidence)

Test System Setup



- Note: 1. Support units were connected to second LISN.
2. Both of LISNs (AMN) 80 cm from EUT and at the least 80 cm from other units and other metal planes support units.

The measurement procedure is in according with CISPR 16-2-1:2013. The related limit was specified in the EN 55022 Class B.

The external I/O cables were draped along the test table and formed a bundle 30 to 40 cm long in the middle.

The spacing between the peripherals was 10 cm.

The adapter was connected to a 230VAC/50 Hz power source.

EMI Test Receiver Setup

The EMI test receiver was set to investigate the spectrum from 150 kHz to 30 MHz.

During the conducted emission test, the EMI test receiver was set with the following configurations:

Frequency Range	IF B/W
150 kHz – 30 MHz	9 kHz

Test Equipment List and Details

Manufacturer	Description	Model	Serial Number	Calibration Date	Calibration Due Date
Rohde & Schwarz	EMI Test Receiver	ESCS30	100176	2013-06-17	2014-06-17
Rohde & Schwarz	LISN	ESH2-Z5	892107/021	2013-08-22	2014-08-22
Schwarzbeck	ISN Cat 5	NTFM 8158	cat 5-8158-0010	2012-11-05	2013-11-05
Rohde & Schwarz	Transient Limiter	ESH3Z2	DE25985	2013-10-15	2014-10-15
Rohde & Schwarz	CE Test software	EMC 32	V8.53	--	--
Rohde & Schwarz	LISN	ENV216	3560.6650.12-101613-Yb	2013-05-07	2014-05-07

* **Statement of Traceability:** Bay Area Compliance Laboratories Corp. (Shenzhen) attests that all calibrations have been performed in accordance to requirements, traceable to National Primary Standards and International System of Units (SI).

Test Procedure

Maximizing procedure was performed on the six (6) highest emissions to ensure EUT compliance using all installation combination.

All data was recorded in the Quasi-peak and average detection mode.

Corrected Factor & Margin Calculation

The Corrected factor is calculated by adding LISN/ISN VDF (Voltage Division Factor) Cable Loss and Transient Limiter Attenuation. The basic equation is as follows:

$$\text{Correction Factor} = \text{LISN/ISN VDF} + \text{Cable Loss} + \text{Transient Limiter Attenuation}$$

The “**Margin**” column of the following data tables indicates the degree of compliance with the applicable limit. For example, a margin of 7dB means the emission is 7 dB below the limit. The equation for margin calculation is as follows:

$$\text{Margin} = \text{Limit} - \text{Corrected Amplitude}$$

Test Results Summary

According to the recorded data in following table, with the worst margin reading of:

6.2 dB at 3.270000 MHz in the Neutral conducted mode (PoE power supply)

Refer to CISPR16-4-2:2011 and CISPR 16-4-1:2009, the measured level is in compliance with the limit if

$$L_m + U_{(Lm)} \leq L_{lim} + U_{cispr}$$

in BACL, $U_{(Lm)}$ is less than U_{cispr} , if L_m is less than L_{lim} , it implies that the EUT complies with the limit.

Test Data

Environmental Conditions

Temperature:	26 °C
Relative Humidity:	56 %
ATM Pressure:	101.0 kPa

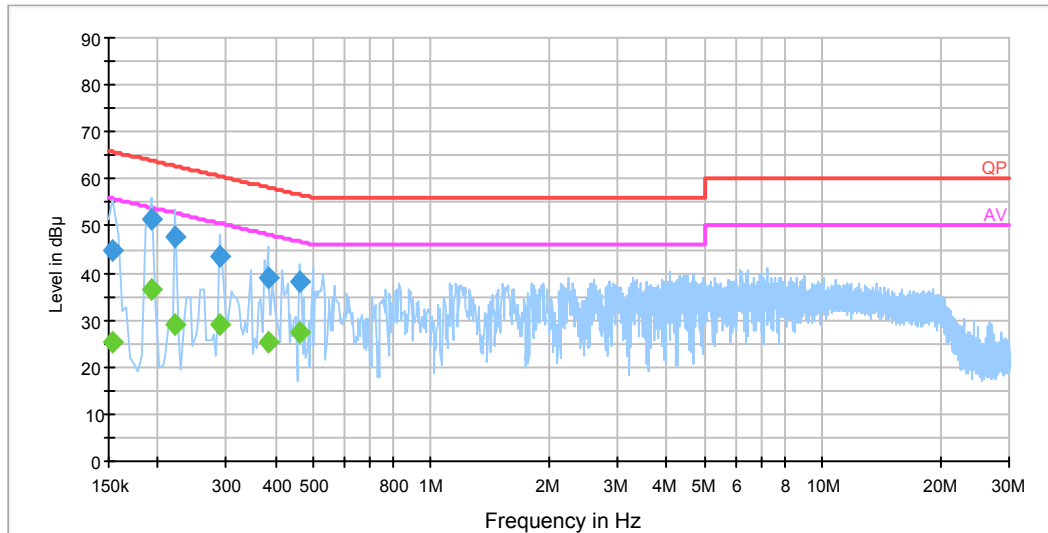
The testing was performed by Joson Xiao on 2013-08-29.

Test Mode: Talking

1) Adapter 1 power supply:

AC 230V/50 Hz, Line

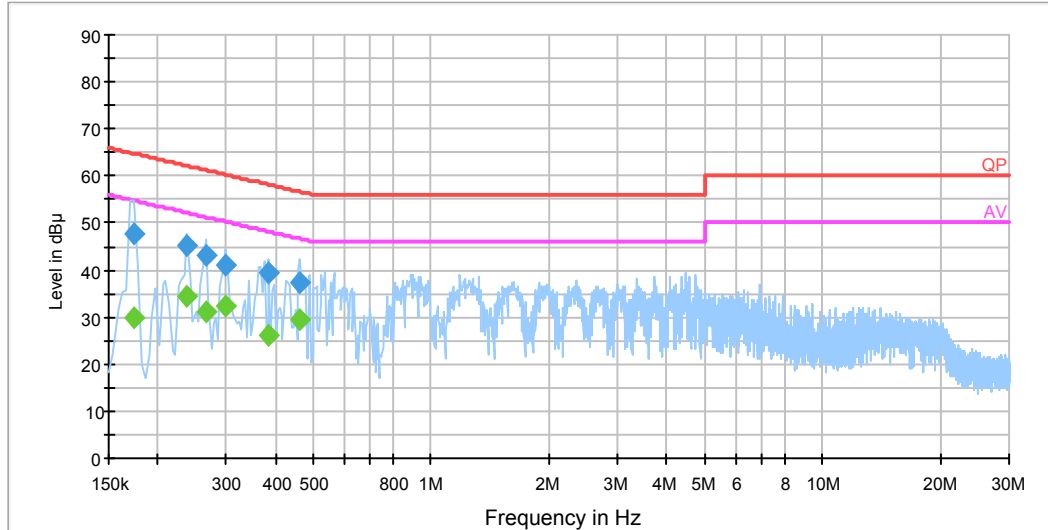
EMI Auto Test L



Frequency (MHz)	Corrected Amplitude (dBμV)	Correction Factor (dB)	Limit (dBμV)	Margin (dB)	Detector (PK/Ave./QP)
0.154000	44.9	19.5	65.8	20.9	QP
0.154000	25.2	19.5	55.8	30.5	Ave.
0.194000	51.4	19.5	63.9	12.5	QP
0.194000	36.3	19.5	53.9	17.5	Ave.
0.222000	47.8	19.5	62.7	15.0	QP
0.222000	29.1	19.5	52.7	23.7	Ave.
0.290000	43.5	19.5	60.5	17.1	QP
0.290000	29.2	19.5	50.5	21.3	Ave.
0.382000	39.2	19.5	58.2	19.1	QP
0.382000	25.1	19.5	48.2	23.1	Ave.
0.462000	38.2	19.5	56.7	18.5	QP
0.462000	27.4	19.5	46.7	19.2	Ave.

AC 230V/50 Hz, Neutral:

EMI Auto Test N

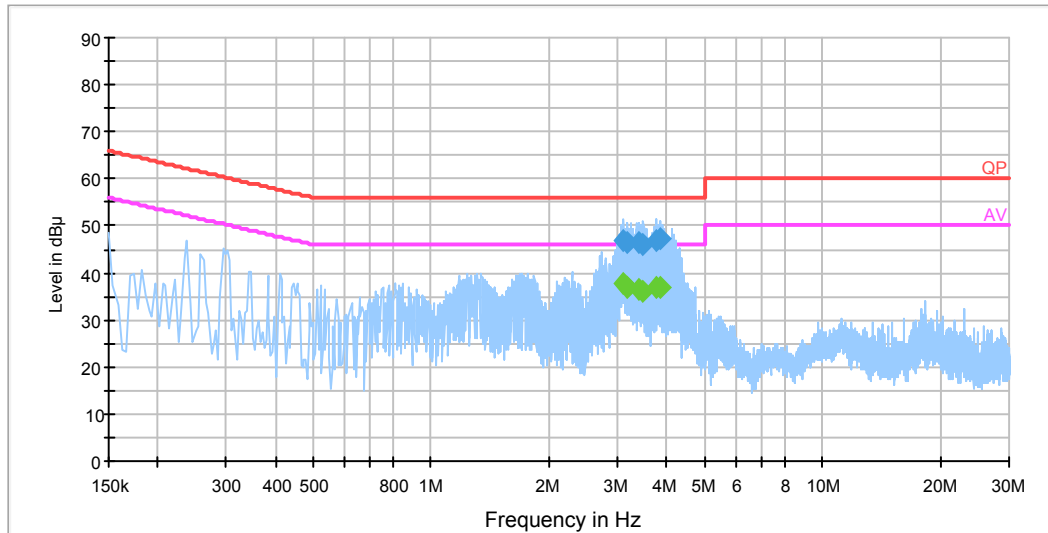


Frequency (MHz)	Corrected Amplitude (dBμV)	Correction Factor (dB)	Limit (dBμV)	Margin (dB)	Detector (PK/Ave./QP)
0.174000	47.5	19.5	64.8	17.2	QP
0.174000	29.8	19.5	54.8	25.0	Ave.
0.238000	45.3	19.5	62.2	16.8	QP
0.238000	34.6	19.5	52.2	17.6	Ave.
0.266000	43.1	19.5	61.2	18.1	QP
0.266000	31.1	19.5	51.2	20.1	Ave.
0.298000	41.1	19.5	60.3	19.2	QP
0.298000	32.4	19.5	50.3	17.9	Ave.
0.386000	39.2	19.5	58.1	18.9	QP
0.386000	26.0	19.5	48.1	22.2	Ave.
0.462000	37.4	19.5	56.7	19.3	QP
0.462000	29.5	19.5	46.7	17.2	Ave.

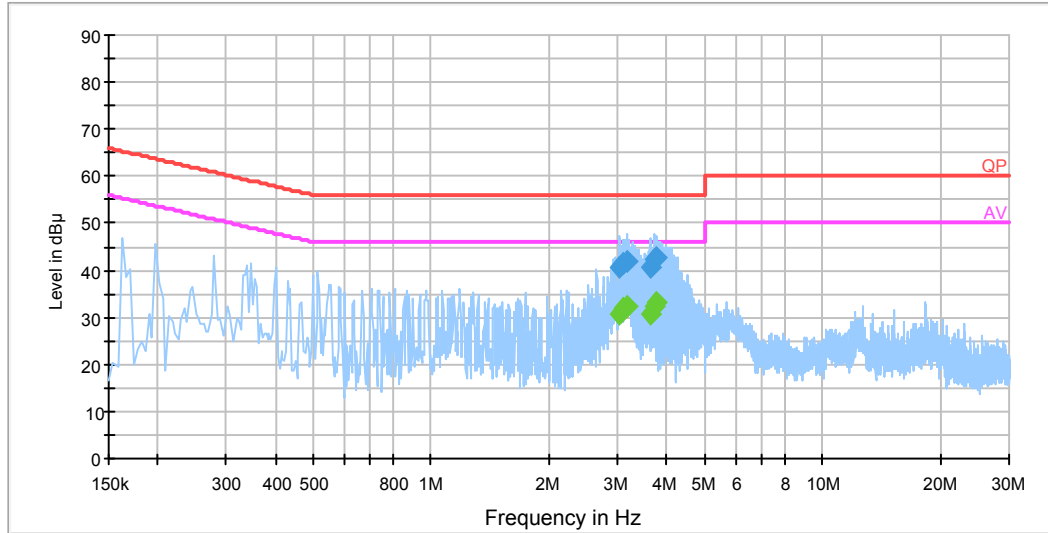
2) Adapter 2 power supply:

AC 230V/50 Hz, Line:

EMI Auto Test L



Frequency (MHz)	Corrected Amplitude (dBμV)	Correction Factor (dB)	Limit (dBμV)	Margin (dB)	Detector (PK/Ave./QP)
3.114000	46.9	19.6	56.0	9.1	QP
3.114000	37.7	19.6	46.0	8.3	Ave.
3.170000	46.3	19.6	56.0	9.7	QP
3.170000	37.0	19.6	46.0	9.0	Ave.
3.410000	46.4	19.6	56.0	9.6	QP
3.410000	36.7	19.6	46.0	9.3	Ave.
3.490000	46.0	19.6	56.0	10.0	QP
3.490000	36.0	19.6	46.0	10.0	Ave.
3.770000	46.8	19.6	56.0	9.2	QP
3.770000	36.7	19.6	46.0	9.3	Ave.
3.834000	47.2	19.6	56.0	8.8	QP
3.834000	37.0	19.6	46.0	9.0	Ave.

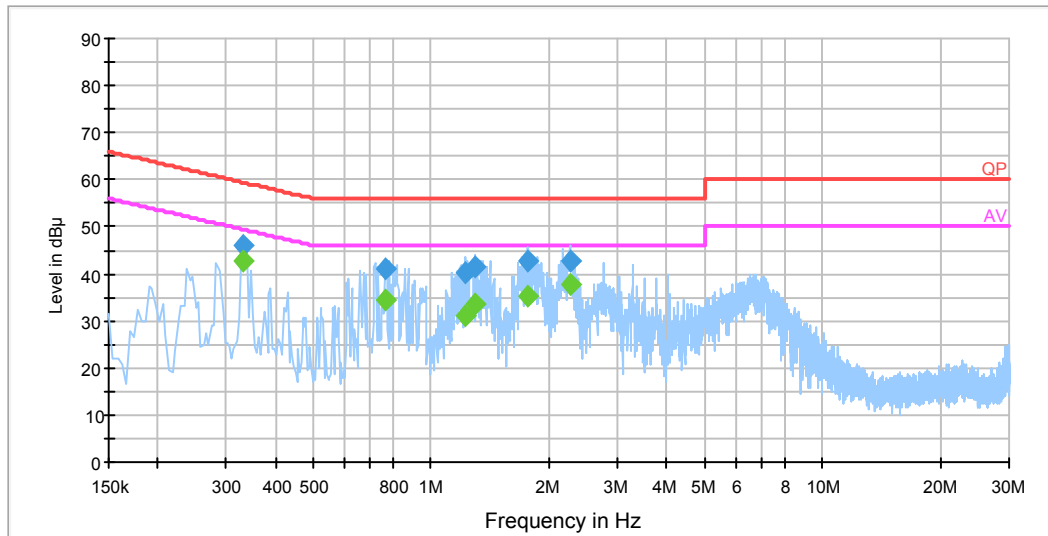
AC 230V/50 Hz, Neutral:**EMI Auto Test N**

Frequency (MHz)	Corrected Amplitude (dBμV)	Correction Factor (dB)	Limit (dBμV)	Margin (dB)	Detector (PK/Ave./QP)
3.034000	40.7	19.6	56.0	15.3	QP
3.034000	30.6	19.6	46.0	15.4	Ave.
3.094000	41.3	19.6	56.0	14.7	QP
3.094000	31.9	19.6	46.0	14.1	Ave.
3.174000	41.8	19.6	56.0	14.2	QP
3.174000	32.3	19.6	46.0	13.7	Ave.
3.618000	40.7	19.6	56.0	15.3	QP
3.618000	30.8	19.6	46.0	15.2	Ave.
3.722000	42.3	19.6	56.0	13.7	QP
3.722000	32.5	19.6	46.0	13.5	Ave.
3.774000	42.9	19.6	56.0	13.1	QP
3.774000	33.1	19.6	46.0	12.9	Ave.

3) PoE power supply:

AC 230V/50 Hz, Line:

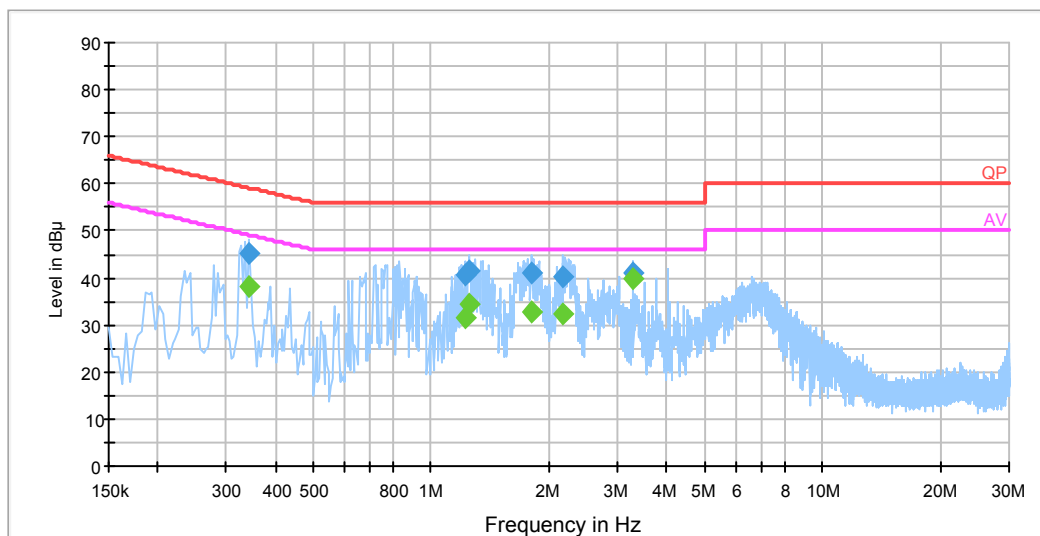
EMI Auto Test L



Frequency (MHz)	Corrected Amplitude (dBμV)	Correction Factor (dB)	Limit (dBμV)	Margin (dB)	Detector (PK/Ave./QP)
0.330000	46.1	19.5	59.5	13.4	QP
0.330000	42.8	19.5	49.5	6.6	Ave.
0.766000	41.0	19.5	56.0	15.0	QP
0.766000	34.5	19.5	46.0	11.5	Ave.
1.226000	40.3	19.5	56.0	15.7	QP
1.226000	31.1	19.5	46.0	14.9	Ave.
1.294000	41.6	19.5	56.0	14.4	QP
1.294000	33.6	19.5	46.0	12.4	Ave.
1.758000	42.5	19.5	56.0	13.5	QP
1.758000	35.3	19.5	46.0	10.7	Ave.
2.262000	42.7	19.5	56.0	13.3	QP
2.262000	37.8	19.5	46.0	8.2	Ave.

AC 230V/50 Hz, Neutral:

EMI Auto Test N

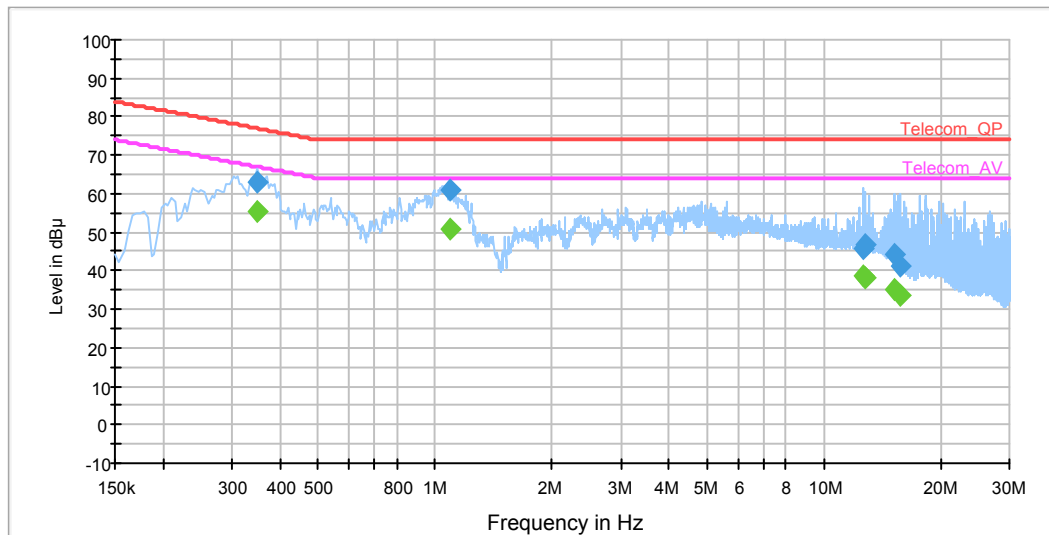


Frequency (MHz)	Corrected Amplitude (dBμV)	Correction Factor (dB)	Limit (dBμV)	Margin (dB)	Detector (PK/Ave./QP)
0.342000	45.3	19.5	59.2	13.8	QP
0.342000	38.0	19.5	49.2	11.2	Ave.
1.230000	40.6	19.5	56.0	15.4	QP
1.230000	31.6	19.5	46.0	14.4	Ave.
1.254000	41.4	19.5	56.0	14.6	QP
1.254000	34.5	19.5	46.0	11.5	Ave.
1.810000	41.2	19.5	56.0	14.8	QP
1.810000	32.9	19.5	46.0	13.1	Ave.
2.170000	40.3	19.6	56.0	15.7	QP
2.170000	32.5	19.6	46.0	13.5	Ave.
3.270000	41.1	19.6	56.0	14.9	QP
3.270000	39.8	19.6	46.0	6.2	Ave.

4) Telecommunication Port:

RJ45 Port:

CAT 5 Auto Test



Frequency (MHz)	Corrected Amplitude (dBμV)	Correction Factor (dB)	Limit (dBμV)	Margin (dB)	Detector (PK/Ave./QP)
0.350000	63.2	19.8	77.0	13.8	QP
0.350000	55.3	19.8	67.0	11.7	Ave.
1.090000	61.0	19.6	74.0	13.0	QP
1.090000	51.0	19.6	64.0	13.0	Ave.
12.674000	45.9	19.5	74.0	28.1	QP
12.674000	38.8	19.5	64.0	25.2	Ave.
12.838000	46.9	19.5	74.0	27.1	QP
12.838000	38.4	19.5	64.0	25.6	Ave.
15.242000	44.2	19.6	74.0	29.8	QP
15.242000	34.9	19.6	64.0	29.1	Ave.
15.638000	41.1	19.6	74.0	32.9	QP
15.638000	33.4	19.6	64.0	30.6	Ave.

Note:

- 1) Corrected Amplitude = Reading + Correction Factor
- 2) Correction Factor = LISN/ISN VDF (Voltage Division Factor) + Cable Loss + Transient Limiter Attenuation
The corrected factor has been input into the transducer of the test software.
- 3) Margin = Limit – Corrected Amplitude

EN 55022 §6-RADIATED DISTURBANCE

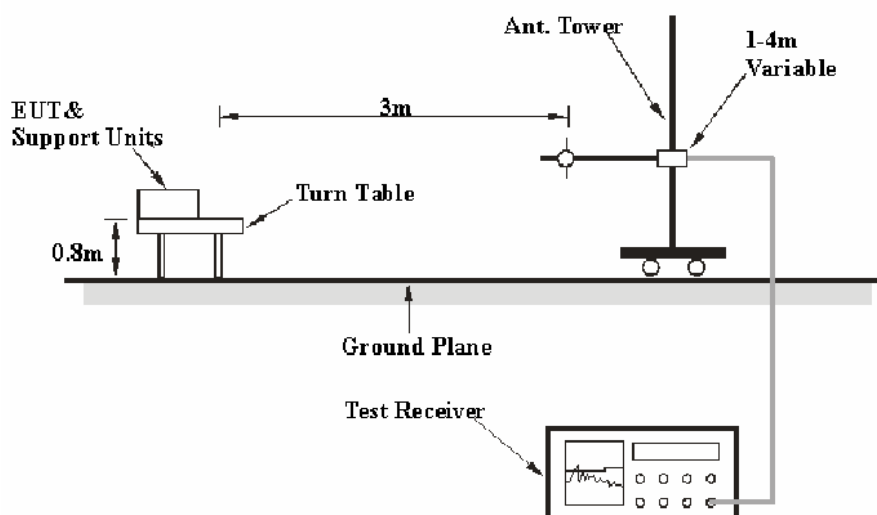
Measurement Uncertainty

All measurements involve certain levels of uncertainties, especially in field of EMC. The factors contributing to uncertainties are spectrum analyzer, cable loss, antenna factor calibration, antenna directivity, antenna factor variation with height, antenna phase center variation, antenna factor frequency interpolation, measurement distance variation, site imperfections, mismatch (average), and system repeatability.

Based on CISPR 16-4-2:2011, the expended combined standard uncertainty of radiation emissions at Bay Area Compliance Laboratories Corp. (Shenzhen) is shown in below table. And the uncertainty will not be taken into consideration for the test data recorded in the report.

Frequency	Polarity	Measurement uncertainty
30MHz~200MHz	Horizontal	4.62 dB (k=2, 95% level of confidence)
	Vertical	4.54 dB (k=2, 95% level of confidence)
200MHz~1GHz	Horizontal	4.84 dB (k=2, 95% level of confidence)
	Vertical	5.91 dB (k=2, 95% level of confidence)
1 GHz~6 GHz	Horizontal/Vertical	4.68 dB (k=2, 95% level of confidence)
Above 6 GHz	Horizontal/Vertical	4.92 dB (k=2, 95% level of confidence)

Test System Setup



The radiated emission tests were performed in the 3 meters chamber A test site, using the setup accordance with the CISPR16-1-4:2012, CISPR 16-2-3:2010. The limit was specified in EN 55022 Class B.

The external I/O cables were draped along the test table and formed a bundle 30 to 40 cm long in the middle.

The spacing between the peripherals was 10 cm.

The adapter was connected to a 230 VAC/50 Hz power source.

EMI Test Receiver Setup

The system was investigated from 30 MHz to 2 GHz.

During the radiated emission test, the EMI test receiver Setup was set with the following configurations:

Frequency Range	RBW	Video B/W	IF B/W	Detector
30 MHz – 1000 MHz	120 kHz	300 kHz	120 kHz	QP
Above 1 GHz	1MHz	3 MHz	/	PK
	1MHz	10 Hz	/	Ave.

Test Equipment List and Details

Manufacturer	Description	Model	Serial Number	Calibration Date	Calibration Due Date
HP	Amplifier	8447E	1937A01046	2013-08-09	2014-08-09
TDK	Chamber	Chamber A	2#	2012-10-15	2015-10-15
Rohde & Schwarz	EMI Test Receiver	ESCI	101120	2012-11-24	2013-11-24
Sunol Sciences	Broadband Antenna	JB1	A040904-2	2011-11-28	2014-11-27
TDK	Chamber	Chamber B	1#	2011-07-23	2014-07-22
Mini-Circuits	Pre-amplifier	ZVA-183-S+	5969001149	2013-04-03	2014-04-03
Sunol Sciences	Horn Antenna	SAS-200/571	135	2012-02-11	2015-02-10
Rohde & Schwarz	Signal Analyzer	FSIQ26	8386001028	2012-11-24	2013-11-23
R&S	Auto test Software	EMC32	V8.53	--	--

* **Statement of Traceability:** Bay Area Compliance Laboratories Corp. (Shenzhen) attests that all calibrations have been performed in accordance to requirements, traceable to National Primary Standards and International System of Units (SI).

Test Procedure

Maximizing procedure was performed on the highest emissions to ensure that the EUT complied with all installation combinations.

All data was recorded in the Quasi-peak detection mode for below 1 GHz, and Peak and Average for above 1 GHz

Corrected Amplitude & Margin Calculation

The Corrected Amplitude is calculated by adding the Antenna Factor and Cable Loss, and subtracting the Amplifier Gain from the Meter Reading. The basic equation is as follows:

$$\text{Corrected Amplitude} = \text{Meter Reading} + \text{Antenna Factor} + \text{Cable Loss} - \text{Amplifier Gain}$$

The “**Margin**” column of the following data tables indicates the degree of compliance with the applicable limit. For example, a margin of 7 dB means the emission is 7 dB below the limit for Class B. The equation for margin calculation is as follows:

$$\text{Margin} = \text{Limit} - \text{Corrected Amplitude}$$

Test Results Summary

According to the data in the following table, with the worst margin reading of:

3.1 dB at 599.006800 MHz in the Vertical polarization (PoE power supply)

Refer to CISPR16-4-2:2011 and CISPR 16-4-1:2009, the measured level is in compliance with the limit if

$$L_m + U_{(Lm)} \leq L_{\text{lim}} + U_{\text{cisp}}r$$

In BACL, $U_{(Lm)}$ is less than $U_{\text{cisp}}r$, if L_m is less than L_{lim} , it implies that the EUT complies with the limit.

Test Data

Environmental Conditions

Temperature:	26 °C
Relative Humidity:	56 %
ATM Pressure:	101.0 kPa

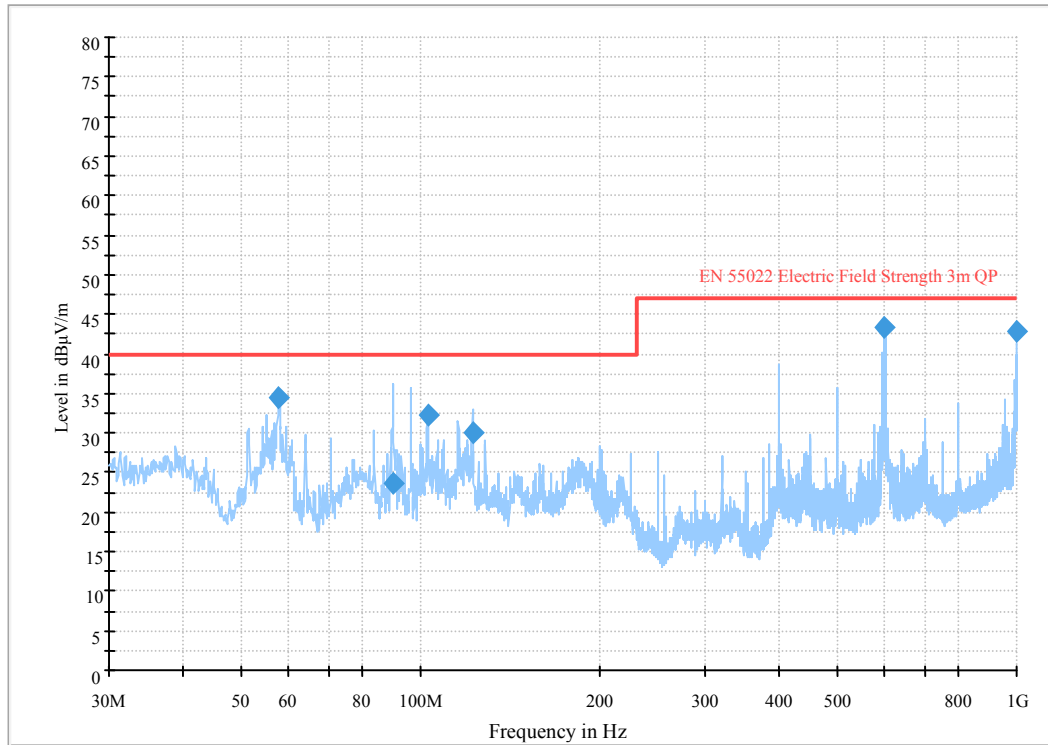
The testing was performed by Joson Xiao on 2013-08-29.

Test Mode: Talking

1) Adapter 1 power supply:

Below 1 GHz:

EN55022



Frequency (MHz)	Corrected Amplitude (dBμV/m)	Antenna height (cm)	Antenna Polarity	Turntable position (degree)	Correction Factor (dB/m)	Limit (dBμV/m)	Margin (dB)
57.867700	34.4	171.0	V	279.0	-20.9	40.0	5.6
89.789100	23.6	197.0	H	137.0	-19.1	40.0	16.4
102.862800	32.3	101.0	V	93.0	-16.5	40.0	7.7
122.117150	30.0	109.0	V	255.0	-13.5	40.0	10.0
601.032750	43.3	102.0	V	8.0	-9.4	47.0	3.7*
999.991000	42.9	121.0	H	197.0	-2.7	47.0	4.1*

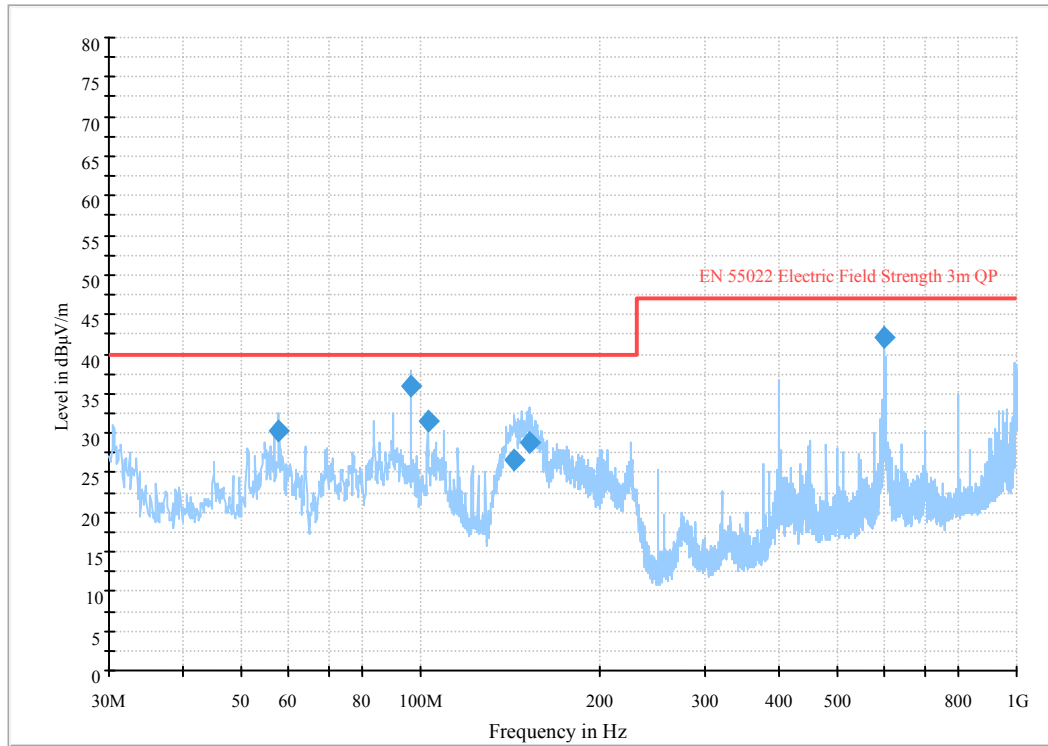
Above 1 GHz:

Frequency (MHz)	Receiver		Turntable Degree	Rx Antenna		Correction Factor (dB/m)	Corrected Amplitude (dBμV/m)	EN 55022	
	Reading (dBμV)	Detector (PK/QP/Ave.)		Height (m)	Polar (H/V)			Limit (dBμV/m)	Margin (dB)
2412.8	35.07	PK	267	1.3	H	6.13	41.20	70	28.8
2412.8	25.37	Ave.	267	1.3	H	6.13	31.50	50	18.5
2412.8	37.31	PK	181	1.3	V	6.13	43.44	70	26.56
2412.8	30.66	Ave.	181	1.3	V	6.13	36.79	50	13.21
3935.8	30.83	PK	146	1.4	V	10.40	41.23	74	32.77
3935.8	18.79	Ave.	146	1.4	V	10.40	29.19	54	24.81
4326.7	30.70	PK	110	1.4	H	11.63	42.33	74	31.67
4326.7	18.72	Ave.	110	1.4	H	11.63	30.35	54	23.65

2) Adapter 2 power supply:

Below 1 GHz:

EN55022



Frequency (MHz)	Corrected Amplitude (dBµV/m)	Antenna height (cm)	Antenna Polarity	Turntable position (degree)	Correction Factor (dB/m)	Limit (dBµV/m)	Margin (dB)
57.845750	30.3	100.0	V	191.0	-20.9	40.0	9.7
96.431500	35.9	100.0	V	335.0	-18.3	40.0	4.1*
102.843050	31.6	103.0	V	352.0	-16.5	40.0	8.4
143.704950	26.5	100.0	V	144.0	-14.5	40.0	13.5
152.203000	28.9	100.0	V	90.0	-15.0	40.0	11.1
599.034100	42.1	104.0	V	353.0	-9.4	47.0	4.9*

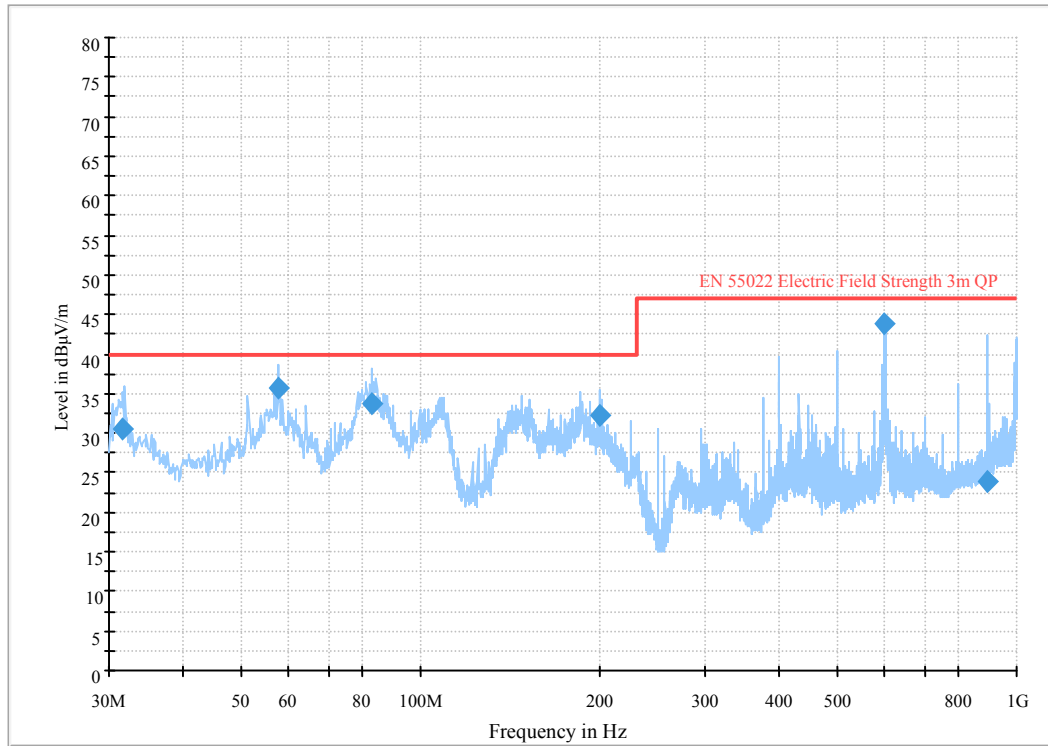
Above 1 GHz:

Frequency (MHz)	Receiver		Turntable Degree	Rx Antenna		Correction Factor (dB/m)	Corrected Amplitude (dB μ V/m)	EN 55022	
	Reading (dB μ V)	Detector (PK/QP/Ave.)		Height (m)	Polar (H/V)			Limit (dB μ V/m)	Margin (dB)
2412.8	39.06	PK	33	1.3	H	6.13	45.19	70	24.81
2412.8	31.39	Ave.	33	1.3	H	6.13	37.52	50	12.48
2412.8	33.04	PK	305	1.5	V	6.13	39.17	70	30.83
2412.8	24.98	Ave.	305	1.5	V	6.13	31.11	50	18.89
4476.9	29.19	PK	176	1.5	V	12.14	41.33	74	32.67
4476.9	19.25	Ave.	176	1.5	V	12.14	31.39	54	22.61
4496.9	30.49	PK	200	1.3	H	12.14	42.63	74	31.37
4496.9	18.78	Ave.	200	1.3	H	12.14	30.92	54	23.08

3) PoE power supply:

Below 1 GHz:

EN55022



Frequency (MHz)	Corrected Amplitude (dBμV/m)	Antenna height (cm)	Antenna Polarity	Turntable position (degree)	Correction Factor (dB/m)	Limit (dBμV/m)	Margin (dB)
31.680200	30.5	104.0	V	131.0	-6.9	40.0	9.5
57.866150	35.7	104.0	V	225.0	-19.4	40.0	4.3*
82.719700	33.7	137.0	V	217.0	-18.5	40.0	6.3
200.014250	32.3	104.0	V	0.0	-12.9	40.0	7.7
599.006800	43.9	104.0	V	13.0	-6.0	47.0	3.1*
894.079050	23.9	222.0	H	211.0	-0.3	47.0	23.1

Above 1 GHz:

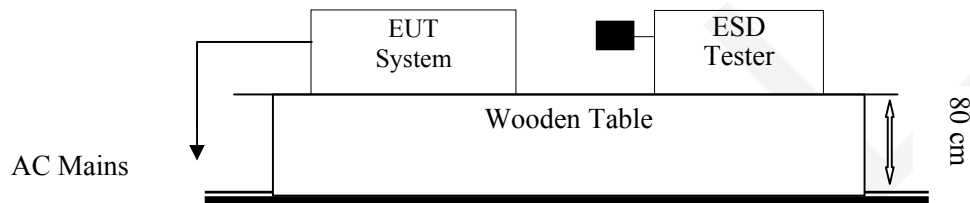
Frequency (MHz)	Receiver		Turntable Degree	Rx Antenna		Correction Factor (dB/m)	Corrected Amplitude (dBμV/m)	EN 55022	
	Reading (dBμV)	Detector (PK/QP/Ave.)		Height (m)	Polar (H/V)			Limit (dBμV/m)	Margin (dB)
2462.9	30.33	PK	302	1.2	H	7.21	37.54	70	32.46
2462.9	20.86	Ave.	302	1.2	H	7.21	28.07	50	21.93
2462.9	30.54	PK	201	1.3	V	7.21	37.75	70	32.25
2462.9	23.04	Ave.	201	1.3	V	7.21	30.25	50	19.75
4837.6	30.62	PK	353	1.3	V	12.40	43.02	74	30.98
4837.6	18.79	Ave.	353	1.3	V	12.40	31.19	54	22.81
4947.8	29.79	PK	302	1.2	H	12.50	42.29	74	31.71
4947.8	19.08	Ave.	302	1.2	H	12.50	31.58	54	22.42

Note: *within measurement uncertainty.

EN 55024 §4.2.1-ELECTROSTATIC DISCHARGES (IEC 61000-4-2)**Test Equipment**

Manufacturer	Description	Model	Serial Number	Calibration Date	Calibration Due Date
EM Test	ESD Tester	Dito	302105	2013-09-13	2014-09-12

* **Statement of Traceability:** Bay Area Compliance Laboratories Corp. (Shenzhen) attests that all calibrations have been performed in accordance to requirements, traceable to National Primary Standards and International System of Units (SI).

Test System Setup

Remark: ■ is the tip of the electrode

IEC 61000-4-2 specifies that a tabletop EUT shall be placed on a non-conducting table which is 80 centimeters above a ground reference plane and that floor mounted equipment shall be placed on a insulating support approximately 10 centimeters above a ground plane. During the tests, the EUT is positioned over a ground reference plane in conformance with this requirement.

For tabletop equipment, a 1.5 by 1.0-meter metal sheet (HCP) is placed on the table and connected to the ground plane via a metal strap with two 470 k Ohms resistors in series. The EUT and attached cables are isolated from this metal sheet by 0.5-millimeter thick insulating material. A Vertical Coupling Plane (VCP) grounded on the ground plane through the same configuration as in the HCP is used.

Test Standard

EN 55024:2010 (IEC 61000-4-2:2008)

Test level 3 for Air Discharge at ± 8 kV

Test level 2 for Contact Discharge at ± 4 kV

Test Level

Level	Test Voltage Contact Discharge ($\pm$ kV)	Test Voltage Air Discharge ($\pm$ kV)
1.	2	2
2.	4	4
3.	6	8
4.	8	15
X.	Special	Special

Performance criterion: B

Test Procedure

Air Discharge:

This test is done on a non-conductive surface. The round discharge tip of the discharge electrode shall be approached as fast as possible to touch the EUT. After each discharge, the discharge electrode shall be removed from the EUT. The generator is then re-triggered for a new single discharge and repeated 10 times for each pre-selected test point. This procedure shall be repeated until all the air discharge completed.

Contact Discharge:

All the procedure shall be same as Section 8.3.1 of IEC 61000-4-2, except that the tip of the discharge electrode shall touch the EUT before the discharge switch is operated.

Indirect discharge for horizontal coupling plane

At least 20 single discharges shall be applied to the horizontal coupling plane, at points on each side of the EUT. The discharge electrode positions vertically at a distance of 0.1 m from the EUT and with the discharge electrode touching the coupling plane.

Indirect discharge for vertical coupling plane

At least 20 single discharges shall be applied to the center of one vertical edge of the coupling plane. The coupling plane, of dimensions 0.5m × 0.5m, is placed parallel to, and positioned at a distance of 0.1m from the EUT. Discharges shall be applied to the coupling plane, with this plane in sufficient different positions that the four faces of the EUT are completely illuminated.

Test Data and Setup Photo

Environmental Conditions

Temperature:	24 °C
Relative Humidity:	50 %
ATM Pressure:	101.0 kPa

The testing was performed by Joson Xiao on 2013-09-05.

Test Mode: Charging & Talking

Table 1: Electrostatic Discharge Immunity (Air Discharge)

EN 61000-4-2 Test Points	Test Levels							
	-2 kV	+2 kV	-4 kV	+4 kV	-8 kV	+8 kV	-15 kV	+15 kV
Front (39 points)	A	A	A	A	B	B	/	/
Back (5 points)	A	A	A	A	A	A	/	/
Top (5 points)	A	A	A	A	A	A	/	/
Left (2 points)	A	A	A	A	A	A	/	/
Right (2 points)	A	A	A	A	A	A	/	/

Table 2: Electrostatic Discharge Immunity (Direct Contact)

EN 61000-4-2 Test Points	Test Levels							
	-2 kV	+2 kV	-4 kV	+4 kV	-6 kV	+6 kV	-8 kV	+8 kV
Back (2 points)	A	A	A	A	/	/	/	/

Table 3: Electrostatic Discharge Immunity (Indirect Contact HCP)

EN 61000-4-2 Test Points	Test Levels							
	-2 kV	+2 kV	-4 kV	+4 kV	-6 kV	+6 kV	-8 kV	+8 kV
Front Side	A	A	A	A	/	/	/	/
Back Side	A	A	A	A	/	/	/	/
Left Side	A	A	A	A	/	/	/	/
Right Side	A	A	A	A	/	/	/	/

Table 4: Electrostatic Discharge Immunity (Indirect Contact VCP)

EN 61000-4-2 Test Points	Test Levels							
	-2 kV	+2 kV	-4 kV	+4 kV	-6 kV	+6 kV	-8 kV	+8 kV
Front Side	A	A	A	A	/	/	/	/
Back Side	A	A	A	A	/	/	/	/
Left Side	A	A	A	A	/	/	/	/
Right Side	A	A	A	A	/	/	/	/







Note:  represents air discharge,  represents direct contact

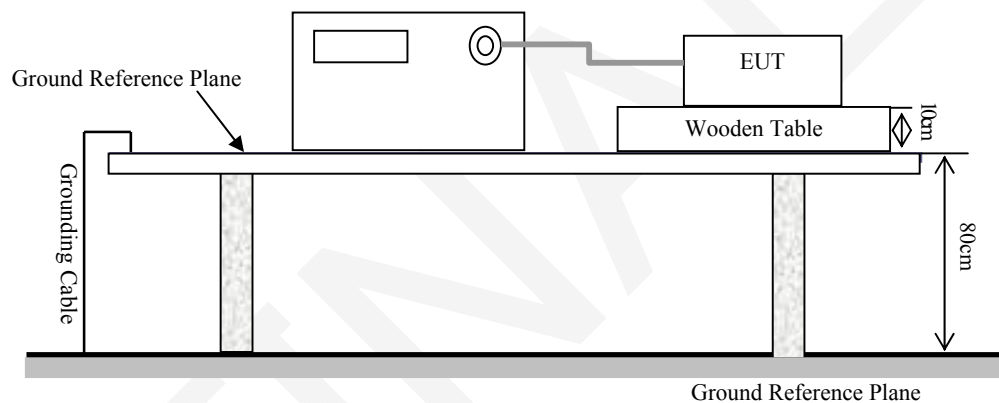


Test Setup Photos

EN 55024 §4.2.2-ELECTRICAL FAST TRANSIENTS (IEC 61000-4-4)**Test Equipment**

Manufacturer	Description	Model	Serial Number	Calibration Date	Calibration Due Date
EM Test	Ultra Compact Generator	UCS 500 N5	V0939105172	2012-11-24	2013-11-23
EM Test	Auto-transformer	MV2616	V0939105173	2012-11-24	2013-11-23
EM Test	EFT Clamp	HFK	0809/59	2012-11-24	2013-11-23

*** Statement of Traceability:** Bay Area Compliance Laboratories Corp. (Shenzhen) attests that all calibrations have been performed in accordance to requirements, traceable to National Primary Standards and International System of Units (SI).

Test System Setup**Test Standard**

EN 55024:2010 (IEC 61000-4-4:2004)

AC mains: Test level 2 at 1 kV

Signal port: Test level 2 at 0.5 kV

Test Level

Open Circuit Output Test Voltage $\pm 10\%$		
Level	On Power Supply Lines	On I/O (Input/Output) Signal data and control lines
1	0.5 kV	0.25 kV
2	1 kV	0.5 kV
3	2 kV	1 kV
4	4 kV	2 kV
X	Special	Special

Performance Criterion: B

Test Procedure

The EUT was arranged for Power Line Coupling and for I/O Line Coupling through a capacitive clamp, where applicable. (Note: The I/O coupling test using a capacitive clamp is performed on the I/O interface cables that are longer in length than 3 meters.) A metal ground plane 2.4 meter by 2.0 meter was placed between the floor and the table and is connected to the earth by a 2.0 meter ground rod. The ground rod is connected to the test facility's electrical earth.

Test Data and Setup Photo

Environmental Conditions

Temperature:	24 °C
Relative Humidity:	50 %
ATM Pressure:	101.0 kPa

The testing was performed by Joson Xiao on 2013-09-05

Test Mode: Charging & Talking

IEC 61000-4-4 Test Points		Test Levels (kV)							
		+0.5	-0.5	+1.0	-1.0	+2.0	-2.0	+4.0	-4.0
AC mains power input ports	L1	/	/	A	A	/	/	/	/
	N	/	/	A	A	/	/	/	/
	PE	/	/	/	/	/	/	/	/
	L1/N	/	/	A	A	/	/	/	/
	L1 /N/PE	/	/	/	/	/	/	/	/
	L/PE	/	/	/	/	/	/	/	/
	N/PE	/	/	/	/	/	/	/	/
Signal ports	RJ45 Port	A	A	/	/	/	/	/	/

AC Mains Port



RJ45 Port



Test Setup Photos

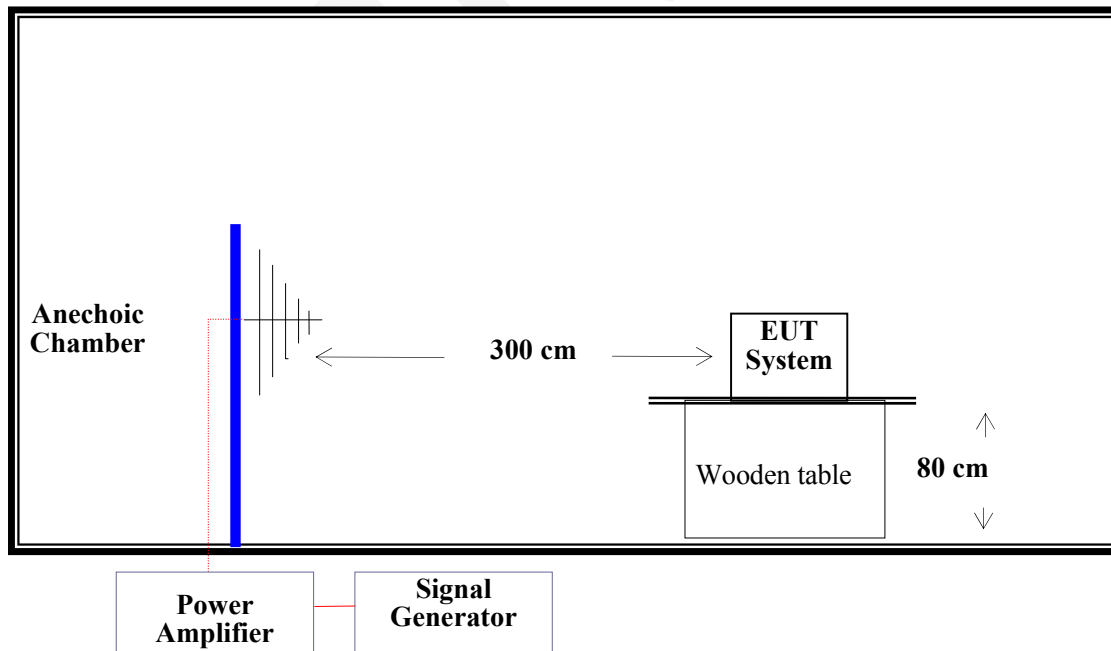
EN 55024 §4.2.3.1-CONTINUOUS RADIATED DISTURBANCES (IEC 61000-4-3)

Test Equipment

Manufacturer	Description	Model	Serial Number	Calibration Date	Calibration Due Date
HP	Signal Generator	8648C	3426A01345	2013-05-09	2014-05-09
Amplifier Research	Power Amplifier	200W1000/M2	H1004497	NCR	NCR
Sunol Sciences	Bi-log Antenna	JB1	A040904-1	NCR	NCR
ETS	Fully Anechoic Chamber	--	--	2012-05-26	2014-05-26
Amplifier Research	Field Meter	FM5004	302149	2013-01-08	2016-01-08
ETS-LINDGREN	Sensor	HI-6005	00069461	2013-01-08	2016-01-08
BK Precision	Sound Level Meter	735	0735 0087 309110025	2012-11-21	2013-11-21
Krohn-hite	Audio Filter	3940	AE2413	2013-05-09	2014-05-09
COM-POWER	PSTN Simulator	LS468	25022	2013-09-12	2014-09-12
HP	RF Communication Test Set	HP8920A	3438A05201	2013-06-14	2014-06-13

* **Statement of Traceability:** Bay Area Compliance Laboratories Corp. (Shenzhen) attests that all calibrations have been performed in accordance to requirements, traceable to National Primary Standards and International System of Units (SI).

Test System Setup



Test Standard

EN 55024:2010 (IEC 61000-4-3: 2006 + A1:2007 + A2:2010)
Test level 2 at 3V / m

Test Level

Level	Field Strength V/m
1.	1
2.	3
3.	10
X.	Special

Performance Criterion: A**Test Procedure**

The EUT and its simulators are placed on a turn table which is 0.8 meter above the ground. The EUT is set 3 meters away from the transmitting antenna which is mounted on an antenna tower. Both horizontal and vertical polarizations of the antenna are set on test. Each of the four sides of EUT must be faced this transmitting antenna and measured individually.

All the scanning conditions are as follows:

In order to judge the EUT performance, a CCD camera is used to monitor the EUT.

All the scanning conditions are as follows:

Condition of Test	Remarks
1. Field Strength	3 V/m (Test level 2)
2. Radiated Signal	AM 80%, 1 kHz Modulation
3. Scanning Frequency	80 – 1000 MHz
4. Sweeping time of radiated	0.0015decade/s
5. Dwell Time	1 sec.

Test Data and Setup Photo**Environmental Conditions**

Temperature:	25 °C
Relative Humidity:	52 %
ATM Pressure:	101.0 kPa

The testing was performed by Joson Xiao on 2013-09-04.

Test Mode: Talking

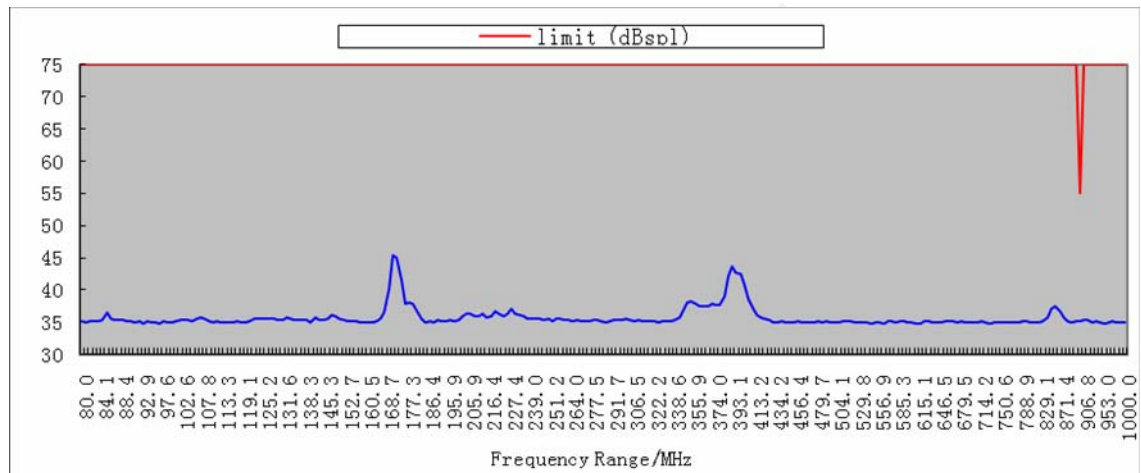
Frequency Range (MHz)	Front Side (3 V/m)		Rear Side (3 V/m)		Left Side (3 V/m)		Right Side (3 V/m)	
	VERT	HORI	VERT	HORI	VERT	HORI	VERT	HORI
80-1000	A	A	A	A	A	A	A	A

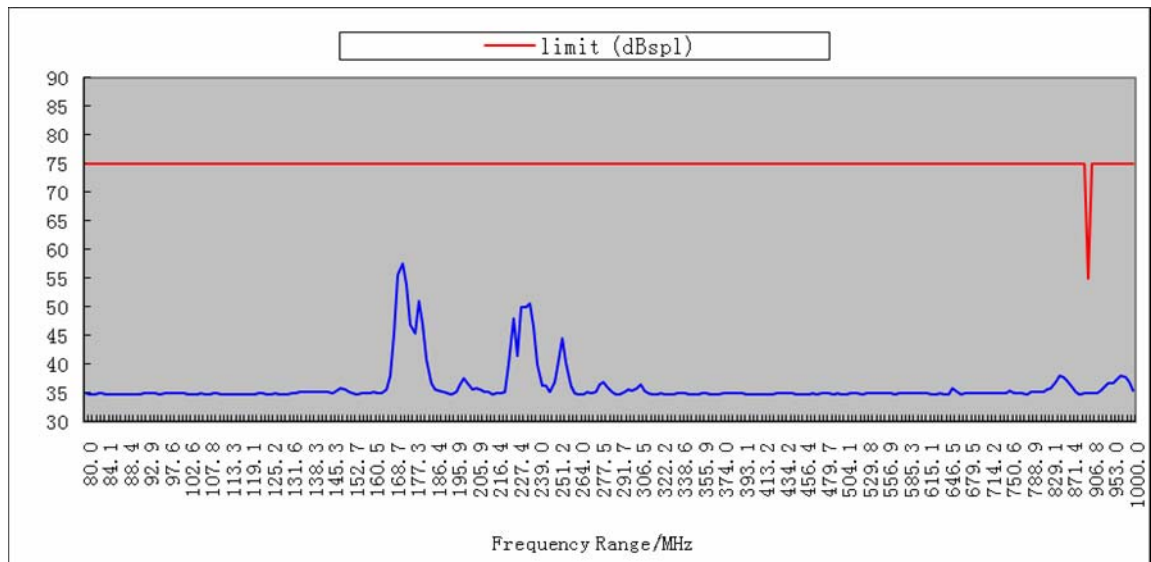
The worst case is recorded as below:

The Acoustic sound pressure level

Vertical:

The worst case is the rear side



Horizontal:**The worst case is the left side****Test Setup Photo**

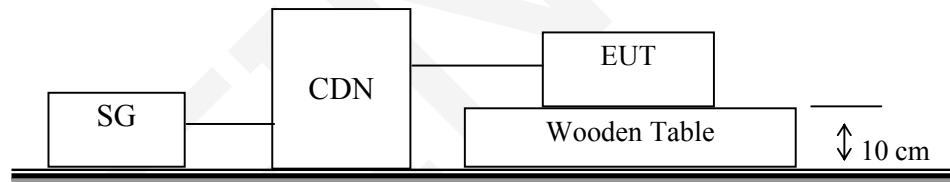
EN 55024 §4.2.3.2-CONTINUOUS CONDUCTED DISTURBANCES (IEC 61000-4-6)

Test Equipment

Manufacturer	Description	Model	Serial Number	Calibration Date	Calibration Due Date
EM Test	CDN	T8RJ45	1101-04	2012-11-24	2013-11-24
EM Test	CDN	M3	1201-05	2012-11-24	2013-11-24
EM Test	C/S Tester	CWS500	303277	2012-11-29	2013-11-29
Amplifier Research	6dB Attenuator	6dB	303282	2012-11-29	2013-11-29
BK Precision	Sound Level Meter	735	0735 0087 309110025	2012-11-21	2013-11-21
Krohn-hite	Audio Filter	3940	AE2413	2013-05-09	2014-05-09
COM-POWER	PSTN Simulator	LS468	25022	2013-09-12	2014-09-12
HP	RF Communication Test Set	HP8920A	3438A05201	2013-06-14	2014-06-13

* **Statement of Traceability:** Bay Area Compliance Laboratories Corp. (Shenzhen) attests that all calibrations have been performed in accordance to requirements, traceable to National Primary Standards and International System of Units (SI).

Test Setup



Test Standard

EN 55024:2010 (IEC 61000-4-6:2008)

Test Level 2 at 3 V r.m.s. (unmodulated), 0.15 MHz ~ 80 MHz

Test Level

Level	Voltage Level (r.m.s.) (V)
1	1
2	3
3	10
X	Special

Performance Criterion: A

Test Procedure

- 1) Let the EUT work in test mode and test it.
- 2) The EUT are placed on an insulating support 0.1 m high above a ground reference plane. CDN (coupling and decoupling device) is placed on the ground plane about 0.3 m from EUT. Cables between CDN and EUT are as short as possible, and their height above the ground reference plane shall be between 30 and 50 mm (where possible).
- 3) The disturbance signal described below is injected to EUT through CDN.
- 4) The EUT operates within its operational mode(s) under intended climatic conditions after power on.
- 5) The frequency range is swept from 150 kHz to 80 MHz using 3V signal level, and with the disturbance signal 80% amplitude modulated with a 1KHz sine wave.
- 6) The rate of sweep shall not exceed 1.5×10^{-3} decades/s. Where the frequency is swept incrementally, the step size shall not exceed 1% of the start and thereafter 1% of the preceding frequency value.
- 7) An artificial ear and sound level meter are used to monitor the sound pressure level. RF communication test set is used to monitor the noise level.
- 8) Recording the EUT operating situation during compliance testing and decide the EUT immunity criterion.

Test Data and Setup Photo

Environmental Conditions

Temperature:	25 °C
Relative Humidity:	52 %
ATM Pressure:	101.0 kPa

The testing was performed by Joson Xiao on 2013-09-04.

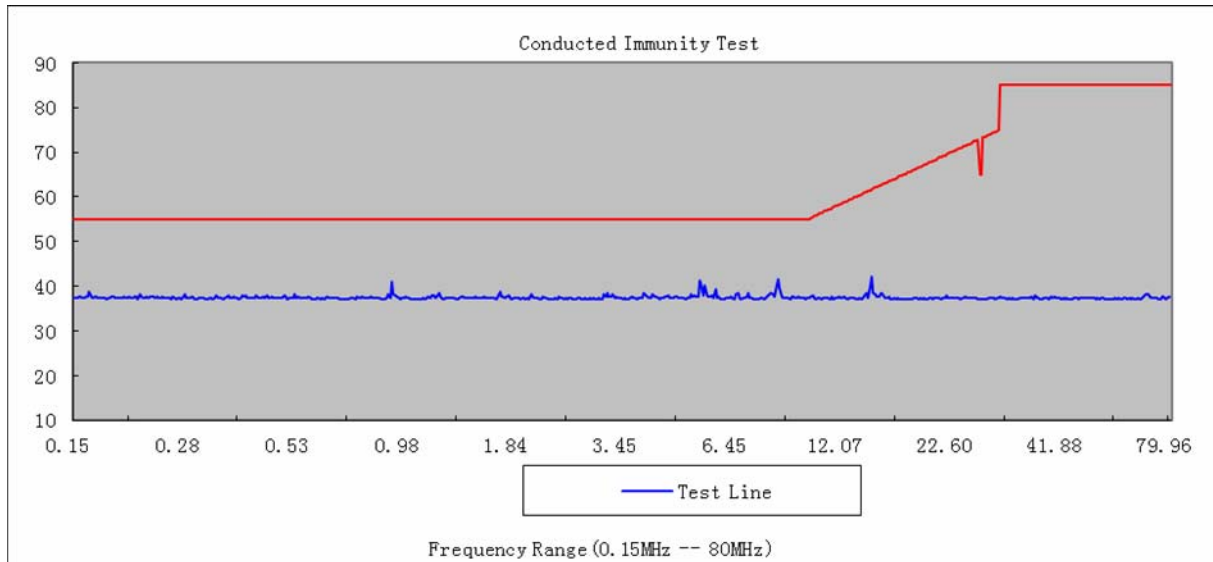
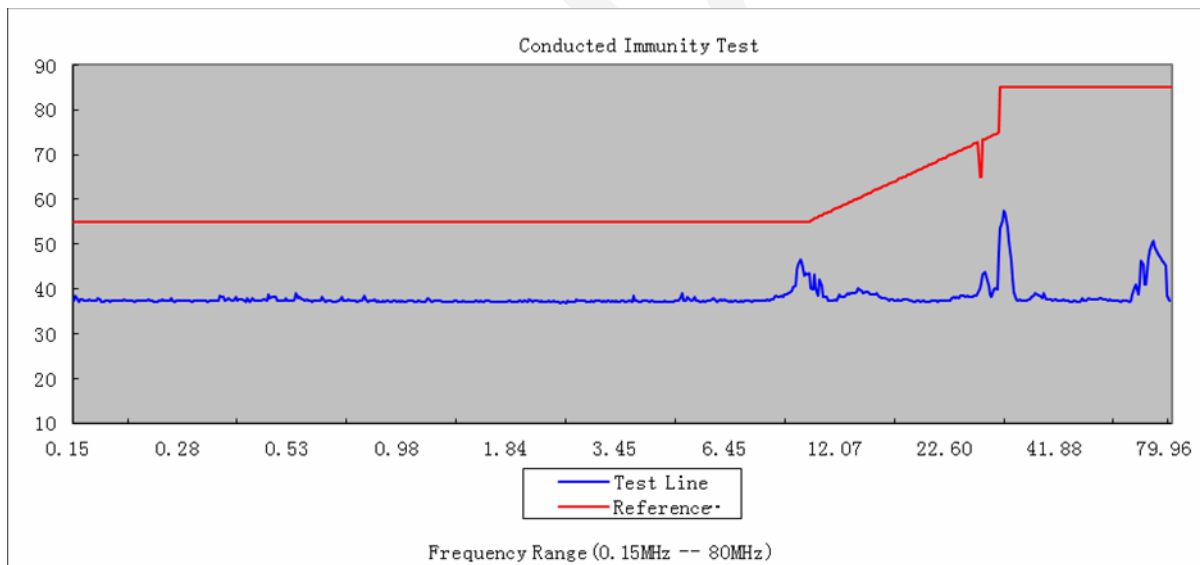
Test Mode: Talking

Table 1: AC mains power input port**Modulation:** Amplitude 80%, 1 kHz sine wave**Test level:** 3V r.m.s.

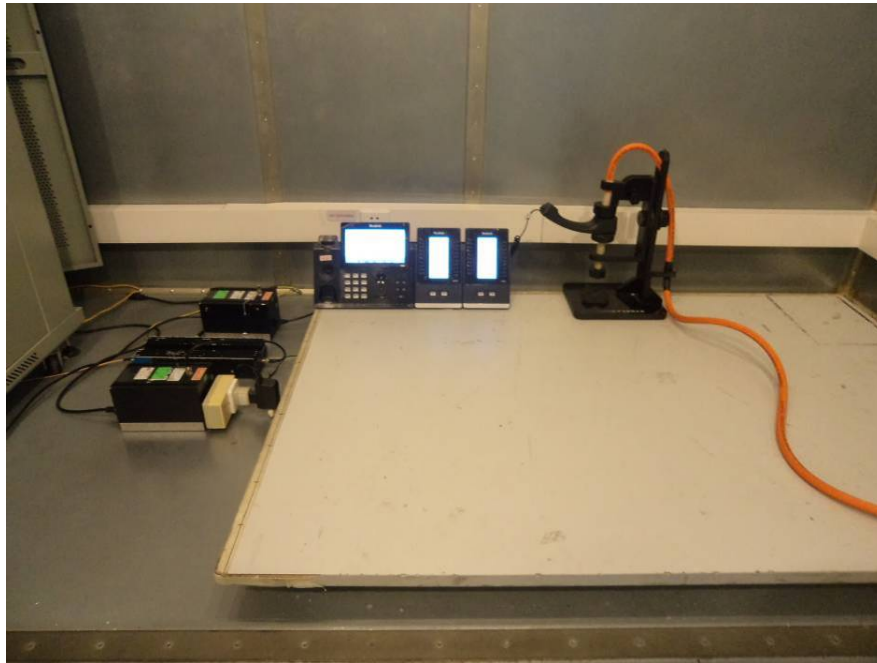
Level	Voltage Level (r.m.s.) U_0	Pass	Fail
1	1	/	/
2	3	A	/
3	10	/	/
X	Special	/	/

Table 2: RJ45 port**Modulation:** Amplitude 80%, 1 kHz sine wave**Test level:** 3V r.m.s.

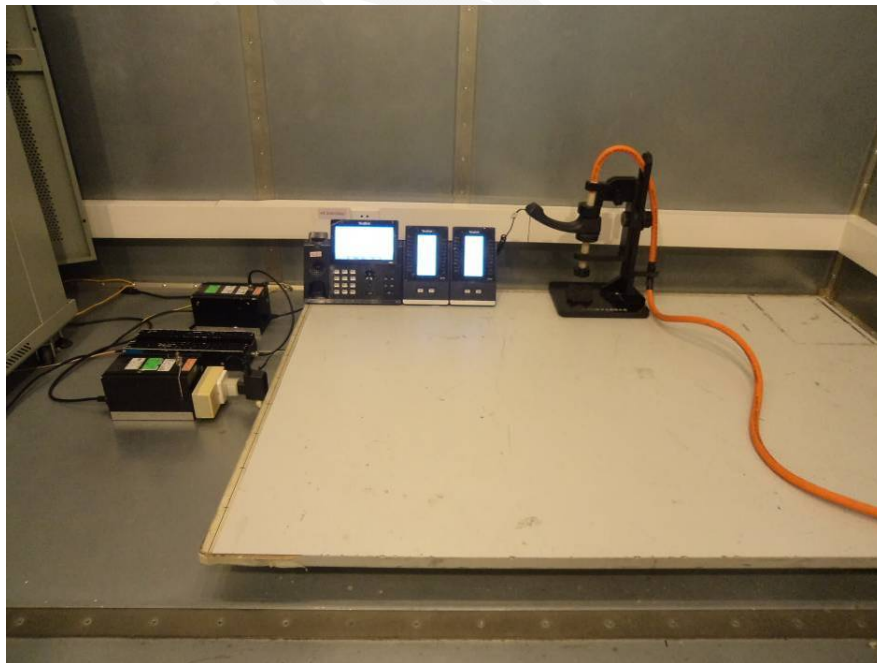
Level	Voltage Level (r.m.s.) U_0	Pass	Fail
1	1	/	/
2	3	A	/
3	10	/	/
X	Special	/	/

CS (0.15MHz-80MHz)**The Acoustic sound pressure level-AC Mains Port****The Acoustic sound pressure level-RJ45 Port**

AC Mains Port



RJ45 Port

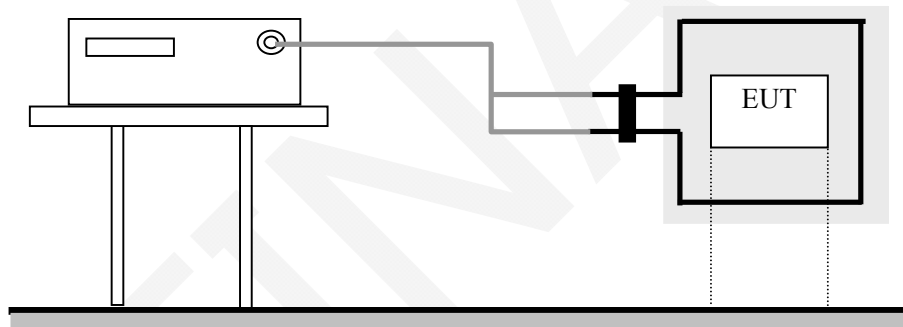


Test Setup Photos

EN 55024 §4.2.4-POWER FREQUENCY MAGNETIC FIELDS (IEC 61000-4-8)**Test Equipment**

Manufacturer	Description	Model	Serial Number	Calibration Date	Calibration Due Date
EM Test	EMS Combination Tester	UCS 500 N5	V0939105172	2012-11-24	2013-11-23
EM Test	AC Source	MV2616	V0939105173	2012-11-24	2013-11-23
EM Test	Loop Antenna	MS100	0809-05	2012-11-17	2013-11-16
EW BELL	ELF Gauss/Tesla Meter	4190	0911011	2012-12-25	2013-12-24
EM TEST	Current Transformer	MC 2630	0309-59	2012-11-17	2013-11-16

* **Statement of Traceability:** Bay Area Compliance Laboratories Corp. (Shenzhen) attests that all calibrations have been performed in accordance to requirements, traceable to National Primary Standards and International System of Units (SI).

Test Setup**Test Standard**

EN 55024:2010 (IEC 61000-4-8:2009)
Test level 1 at 1A/m

Test Level

Level	Magnetic Field Strength A/m
1	1
2	3
3	10
4	30
5	100
X.	Special

Performance criterion: A

Test Procedure

The EUT shall be subjected to the test magnetic field by using the induction coil of standard dimensions (1 m*1 m). The induction coil shall then be rotated by 90° in order to expose the EUT to the test field with different orientations.

Test Data and Setup Photo

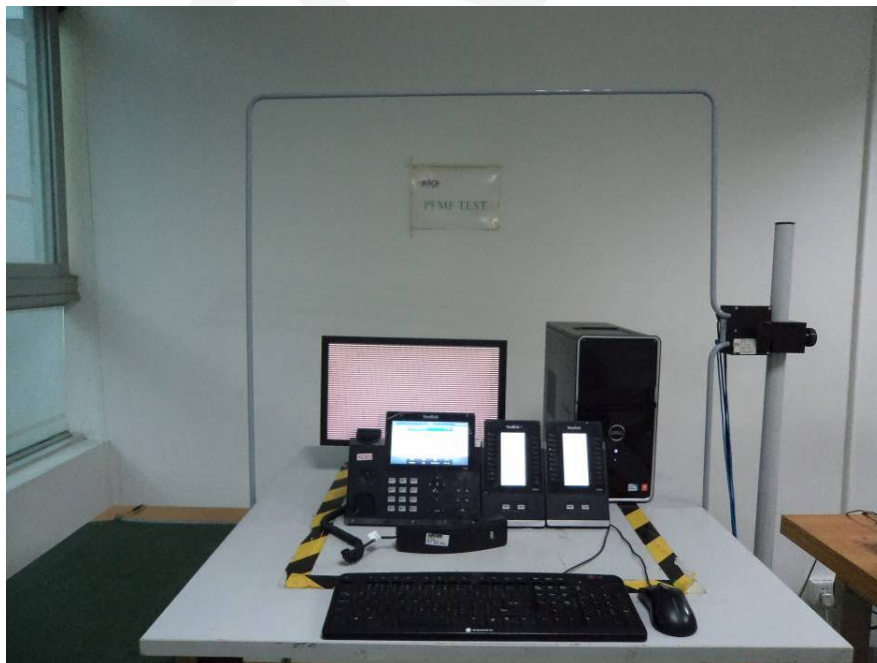
Environmental Conditions

Temperature:	24 °C
Relative Humidity:	50 %
ATM Pressure:	101.0 kPa

The testing was performed by Joson Xiao on 2013-09-05.

Test Mode: Charging & Talking

Level	Magnetic Field Strength A/m	X (Horizontal)	Y (Vertical)	Z (Special)
1	1	A	A	A
2	3	/	/	/
3	10	/	/	/
4	30	/	/	/
5	100	/	/	/
X	Special	/	/	/

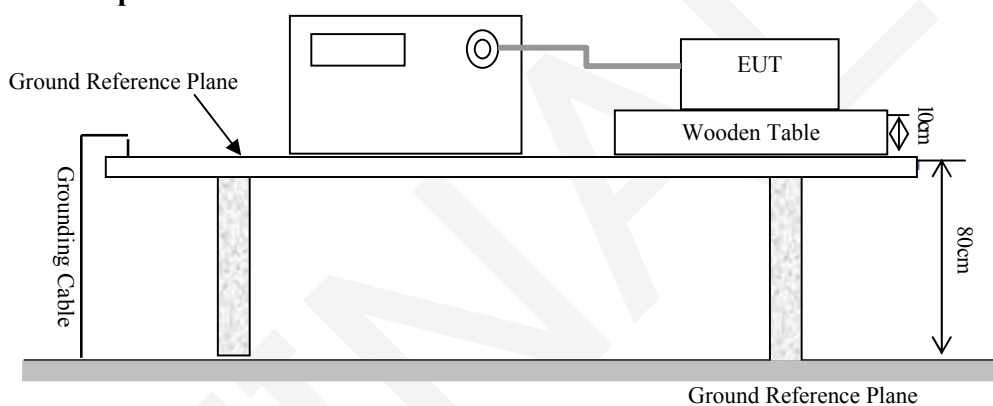


Test Setup Photo

EN 55024 §4.2.5-SURGES (IEC 61000-4-5)**Test Equipment**

Manufacturer	Description	Model	Serial Number	Calibration Date	Calibration Due Date
EM Test	CDN	CNV 504S1	V0939105175	2012-11-24	2013-11-24
EM Test	EMS Combination Tester	UCS 500 N5	V0939105172	2012-11-24	2013-11-24
EM Test	AC Source	MV2616	V0939105173	2012-11-24	2013-11-24

* **Statement of Traceability:** Bay Area Compliance Laboratories Corp. (Shenzhen) attests that all calibrations have been performed in accordance to requirements, traceable to National Primary Standards and International System of Units (SI).

Test System Setup**Test Standard**

EN 55024:2010 (IEC 61000-4-5:2005)

AC Port: Test level 3 at 2 kV (Line-to-Earth)

Test level 2 at 1 kV (Line-to-Line)

Signal port: Line-Ground: Test level 2 at 1 kV

Test Level

Level	Open Circuit Output Test Voltage $\pm 10\%$	Performance Criterion	
		AC Mains	Signal Port
1	0.5 kV	B	C
2	1 kV	B	C
3	2 kV	B	C
4	4 kV	B	C
X	Special	/	/

Test Procedure

- 1) For input a.c. power ports, provide a 1 kV 1.2/50 μ s voltage surge (at open-circuit condition) and a 8/20 μ s current surge into a short circuit.
- 2) For signal ports and telecommunication ports, provide a 0.5 kV 10/700 μ s voltage surge (at open-circuit condition).
- 3) At least 5 positive and 5 negative (polarity) tests with a maximum 1/min repetition rate are conducted during test.
- 4) Different phase angles are done individually.
- 5) Record the EUT operating situation during compliance test and decide the EUT immunity criterion for above each test.

Test Data and Setup Photo

Environmental Conditions

Temperature:	24 °C
Relative Humidity:	50 %
ATM Pressure:	101.0 kPa

The testing was performed by Joson Xiao on 2013-09-05.

Test Mode: Charging & Talking

Table 1: AC mains power input port

Level	Voltage	Poll	Path	Pass	Fail
1	0.5kV	$\pm$	L1-N, L-PE, N-PE, L-N-PE	A	/
2	1kV	$\pm$	L1-N, L-PE, N-PE, L-N-PE	A	/
3	2kV	$\pm$	L-PE, N-PE, L-N-PE	A	/
4	4kV	$\pm$	L-N, L-PE, N-PE	/	/

Table 2: RJ45 port

Level	Voltage	Poll	Path	Pass	Fail
1	0.5kV	$\pm$	Line-Ground	A	/
2	1kV	$\pm$	Line-Ground	A	/
3	2kV	$\pm$	Line-Line, Line-Ground	/	/
4	4kV	$\pm$	Line-Line, Line-Ground	/	/

AC mains Port



RJ45 Port

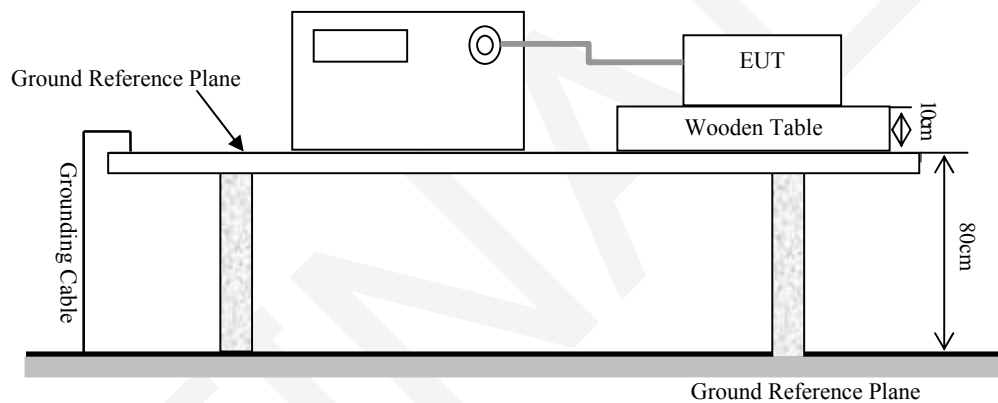


Test Setup Photos

EN 55024 §4.2.6-VOLTAGE DIPS AND INTERRUPTIONS (IEC 61000-4-11)**Test Equipment**

Manufacturer	Description	Model	Serial Number	Calibration Date	Calibration Due Date
EM Test	Ultra Compact Generator	UCS 500 N5	V0939105172	2012-11-24	2013-11-23
EM Test	Auto-transformer	MV2616	V0939105173	2012-11-24	2013-11-23

* **Statement of Traceability:** Bay Area Compliance Laboratories Corp. (Shenzhen) attests that all calibrations have been performed in accordance to requirements, traceable to National Primary Standards and International System of Units (SI)..

Test Setup**Test Standard**

EN 55024:2010 (IEC 61000-4-11:2004)
Test levels and Performance Criterion

Test Level

Test Level	Voltage dip and short interruptions %UT	Duration (Periods)	Performance Criterion
1	>95	0.5	B
2	30	25	C
3	>95	250	C

Test Procedure

- 1) The interruption is introduced at selected phase angles with specified duration.
- 2) Record any degradation of performance.

Test Data and Setup Photo**Environmental Conditions**

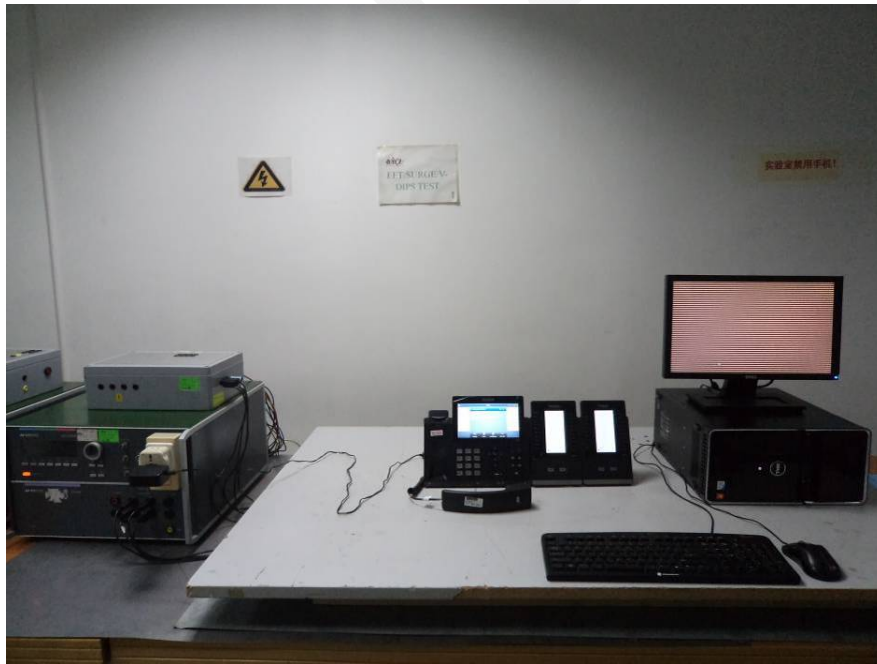
Temperature:	24 °C
Relative Humidity:	50 %
ATM Pressure:	101.0 kPa

The testing was performed by Joson Xiao on 2013-09-05.

Test Mode: Charging & Talking

Level	U2 (% Reduction)	Td(Periods)	Phase Angle	N	Pass	Fail
1	0	0.5	0/180	3	A	/
2	70	25	0/180	3	A	/
3	0	250	0/180	3	C	/

Note: "C" represents the call of the EUT was suspended during the test and needed to redial.



Test Setup Photo

EN 61000-3-2 – HARMONIC CURRENT EMISSIONS

According to EN 61000-3-2:2006 + A1:2009 + A2:2009 section 7: Equipment with a rated power of 75 W or less, other than lighting equipment, are not included in this standard.

FINAL

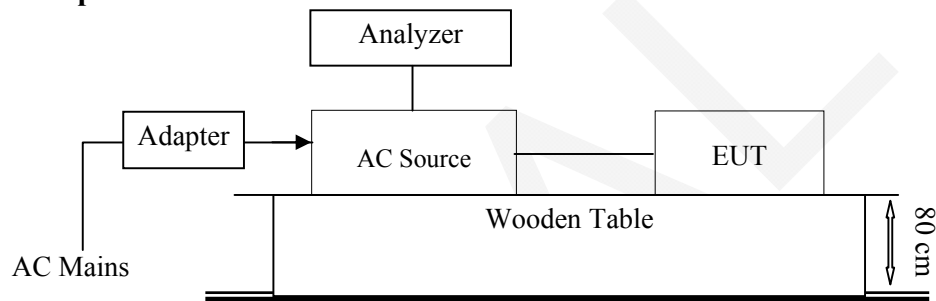
EN 61000-3-3 – VOLTAGE FLUCTUATION AND FLICKER

Test Equipment

Manufacturer	Description	Model	Serial Number	Calibration Date	Calibration Due Date
EM Test	Harmonic/Flicker Analyzer	DPA 500N	V0939105176	2012-11-24	2013-11-23
EM Test	AC Source	ACS500	303276	2011-04-11	2014-04-10

*** Statement of Traceability:** Bay Area Compliance Laboratories Corp. (Shenzhen) attests that all calibrations have been performed in accordance to requirements, traceable to National Primary Standards and International System of Units (SI).

Test System Setup



Test Standard

EN 61000-3-3:2008

Flicker Test Limits:

The limits shall be applicable to voltage fluctuations and flicker at the supply terminals of the equipment under test, measured or calculated according to clause 4 under test conditions described in clause 6 and annex A. Tests made to prove compliance with the limits are considered to be type tests.

The following limits apply:

- the value of Pst shall not be greater than 1,0;
 - the value of Plt shall not be greater than 0,65;
 - the value of d(t) during a voltage change shall not exceed 3,3 % for more than 500 ms;
 - the relative steady-state voltage change, dc, shall not exceed 3,3 %;
 - the maximum relative voltage change dmax, shall not exceed
 - a) 4 % without additional conditions;
 - b) 6 % for equipment which is:
 - switched manually, or
 - switched automatically more frequently than twice per day, and also has either a delayed restart (the delay being not less than a few tens of seconds), or manual restart, after a power supply interruption.
- NOTE: The cycling frequency will be further limited by the Pst and Plt limit. For example: a dmax of 6 % producing a rectangular voltage change characteristic twice per hour will give a Plt of about 0.65.

c) 7 % for equipment which is

- attended whilst in use (for example: hair dryers, vacuum cleaners, kitchen equipment such as mixers, garden equipment such as lawn mowers, portable tools such as electric drills), or
- switched on automatically, or is intended to be switched on manually, no more than twice per day, and also has either a delayed restart (the delay being not less than a few tens of seconds) or manual restart, after a power supply interruption.

In the case of equipment having several separately controlled circuits in accordance with 6.6, limits b) and c) shall apply only if there is delayed or manual restart after a power supply interruption; for all equipment with automatic switching which is energized immediately on restoration of supply after a power supply interruption, limits a) shall apply; for all equipment with manual switching, limits b) or c) shall apply depending on the rate of switching. Pst and Plt requirements shall not be applied to voltage changes caused by manual switching. The limits shall not be applied to voltage changes associated with emergency switching or emergency interruptions.

Test Data and Setup Photo

Environmental Conditions

Temperature:	24 °C
Relative Humidity:	56 %
ATM Pressure:	101.0 kPa

Date of test:	18:40 16 Oct. 2013
Tester:	Joson Xiao
Standard used:	EN 61000-3-3 Flicker
Long time (Pst):	10 min
Observation time:	120 min (12 Flicker measurements)
Flicker meter:	230V / 50Hz
Customer:	Yealink (Xiamen) Network Technology Co., Ltd.
E. U. T.:	IP Phone
Model:	T48G
EUT Operation Mode:	Talking

Maximum Flicker results

	EUT values	Limit	Result
Pst	0.038	1.00	Pass
Plt	0.029	0.65	Pass
dc [%]	0.015	3.30	Pass
dmax [%]	0.279	4.00	Pass
dt [s]	0.000	0.50	Pass

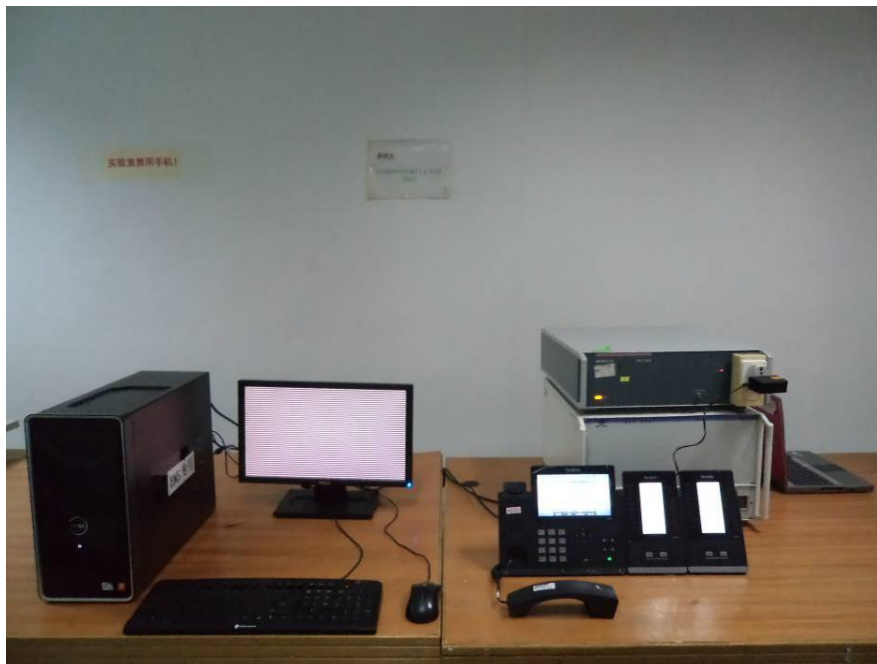
**Test Setup photo**

EXHIBIT A - PRODUCT LABELING

Proposed CE Label Format



Specifications: The marking set out above must be affixed to the apparatus or to its data plate and have a minimum height of 5 mm. The elements should be easily readable and indelible. They may be placed anywhere on the apparatus case or in its battery compartment. No tool should be needed to view the marking.

Proposed Label Location on EUT



EXHIBIT B - EUT PHOTOGRAPHS

EUT – All View



EUT – Front View



EUT – Rear View



EUT – Top View



EUT – Bottom View



EUT – Left View



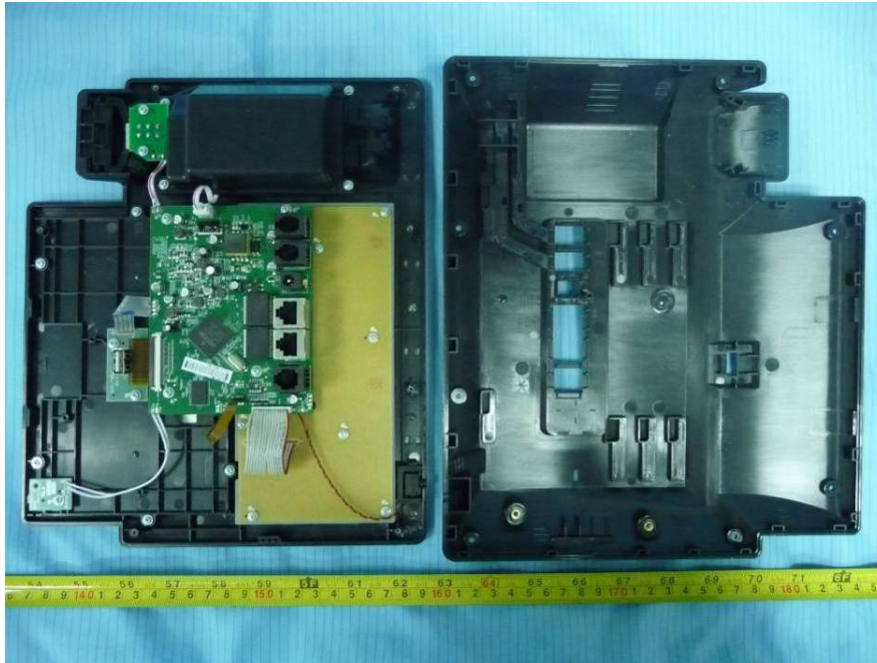
EUT – Right View



EUT – Handset off View



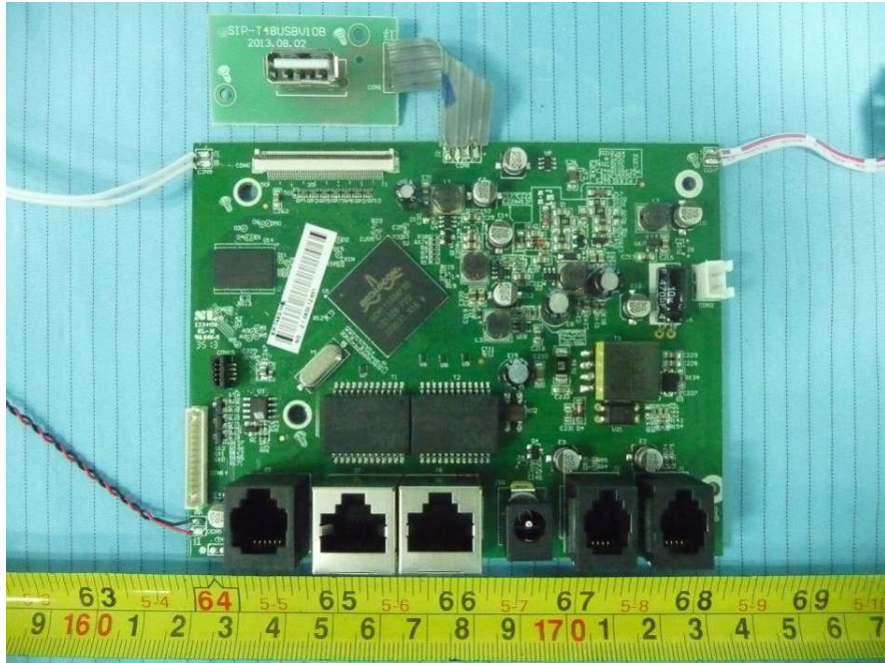
EUT – Base Cover off View 1



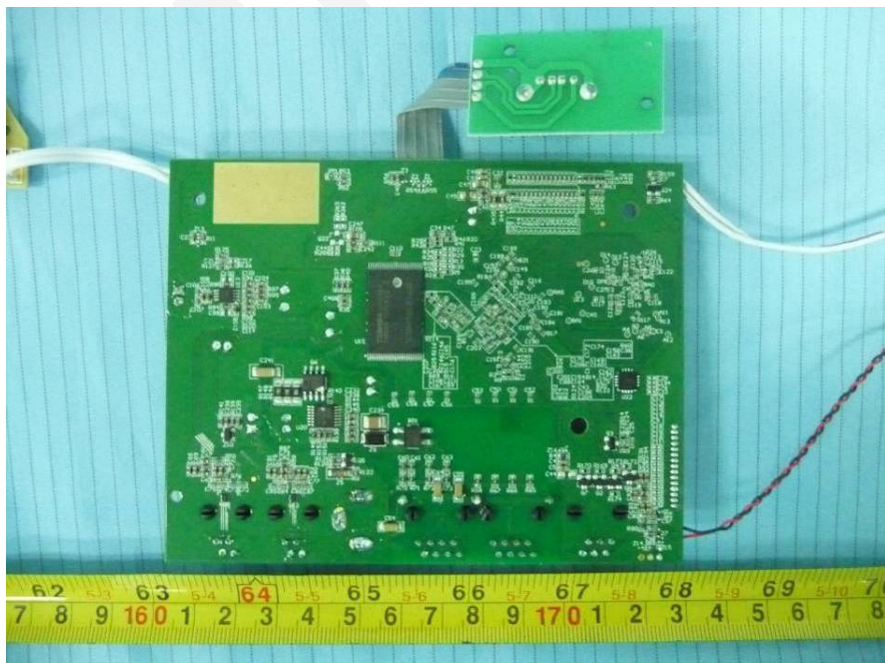
EUT – Base Cover off View 2



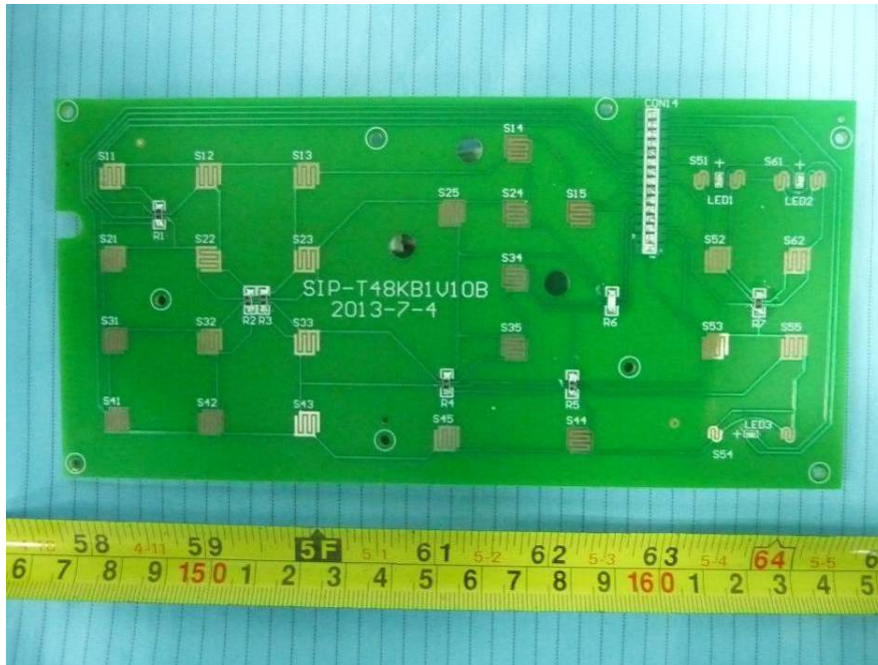
EUT – Main Board and USB Port Board Top View



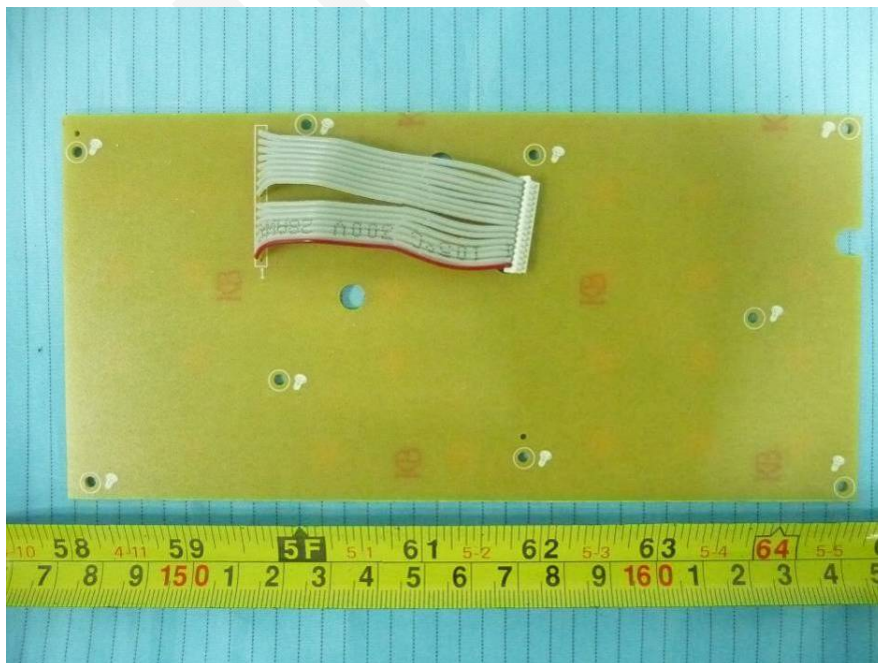
EUT – Main Board and USB Port Board Bottom View



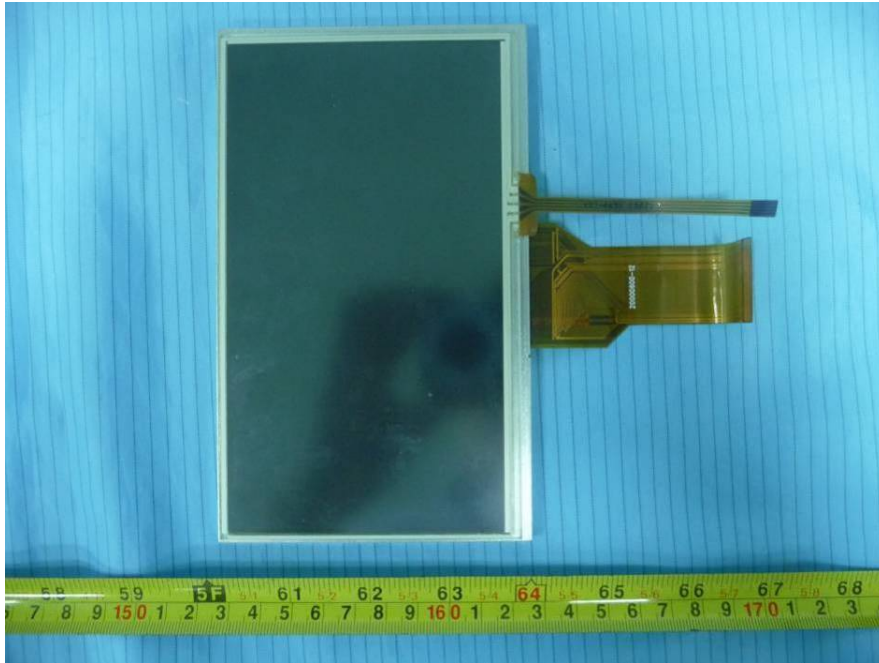
EUT – Key Board Top View



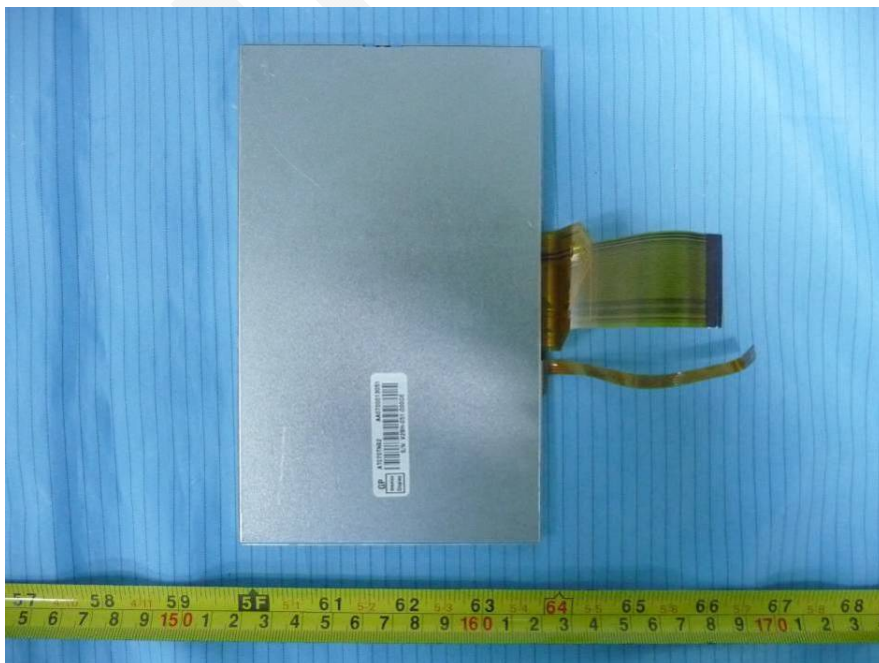
EUT – Key Board Bottom View



EUT – LCD Top View



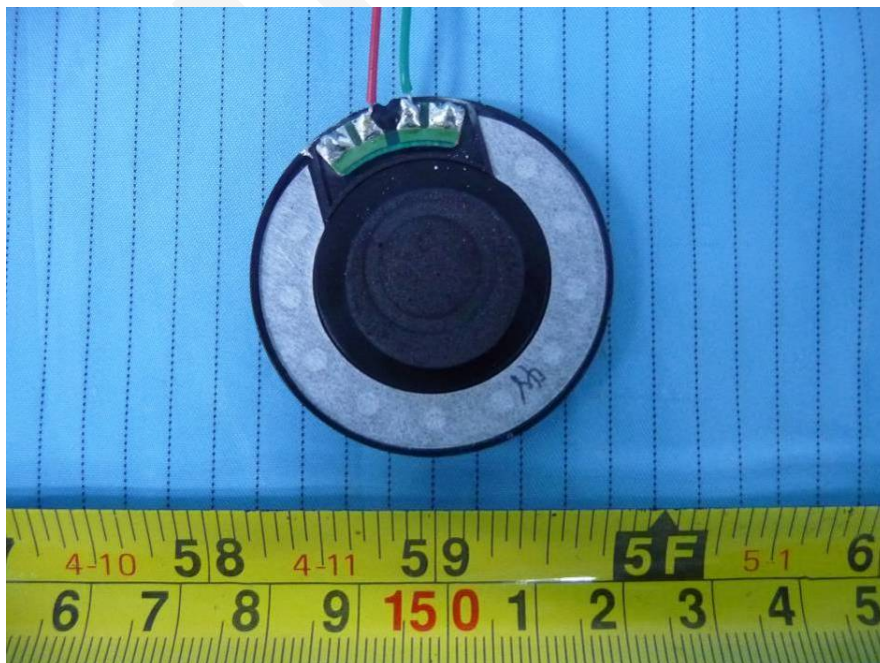
EUT – LCD Bottom View



EUT – Handset Cover off View



EUT – Handset receiver Top View



EUT – Handset receiver Bottom View



EUT – Handset Microphone Top View



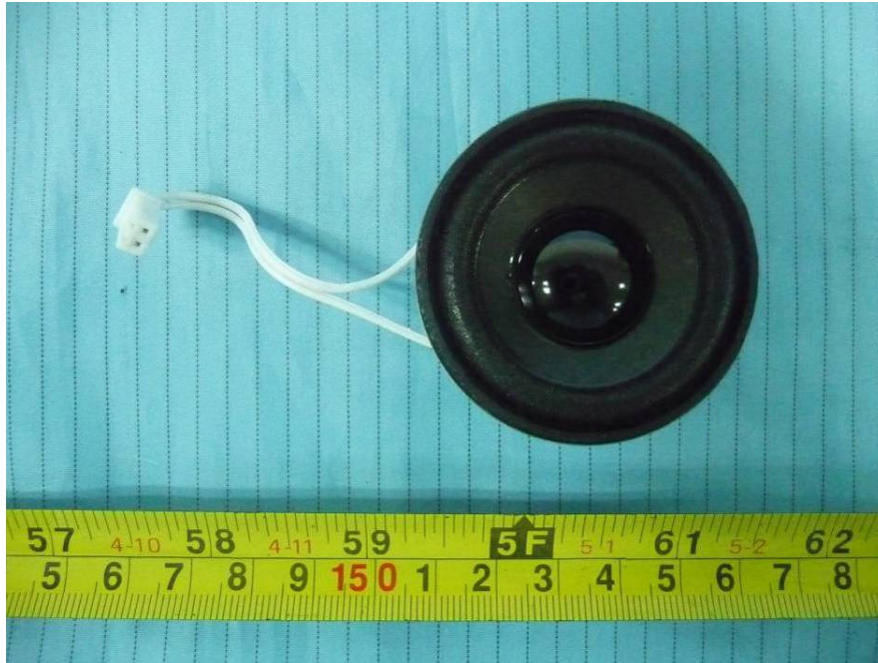
EUT – Handset Microphone Bottom View



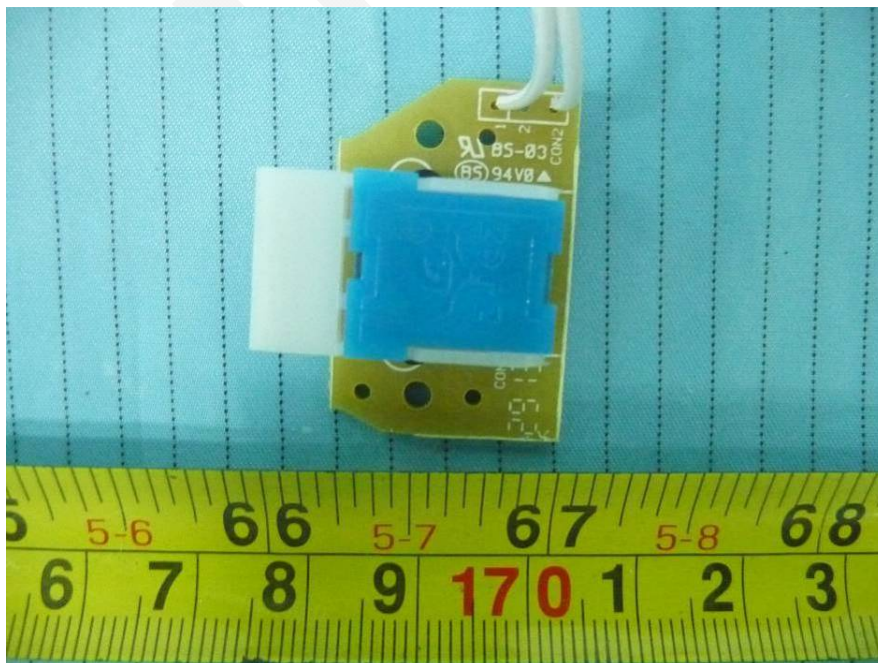
EUT – Speaker Top View



EUT – Speaker Bottom View



EUT – Hook Board Top View



EUT – Hook Board Bottom View



EUT – LED Board Top View



EUT – LED Bottom View



EUT – Adapter 1 Label View



EUT – Adapter 2 Label View



EXHIBIT C - TEST SETUP PHOTOGRAPHS

Conducted Disturbance - Front View (Adapter 1 power supply)



Conducted Disturbance - Side View (Adapter 1 power supply)



Conducted Disturbance - Front View (Adapter 2 power supply)



Conducted Disturbance - Side View (Adapter 2 power supply)



Conducted Disturbance - Front View (PoE power supply)



Conducted Disturbance - Side View (PoE power supply)



Conducted Disturbance - Front View (RJ45 Port)



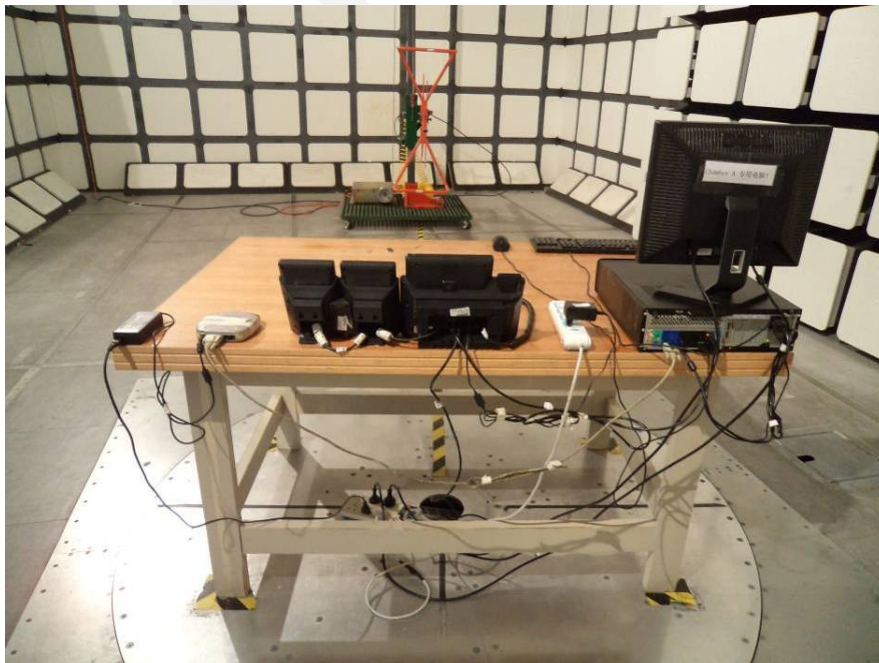
Conducted Disturbance - Side View (RJ45 Port)



Below 1 GHz: Radiated Disturbance - Front View (Adapter 1 power supply)



Below 1 GHz: Radiated Disturbance - Rear View (Adapter 1 power supply)



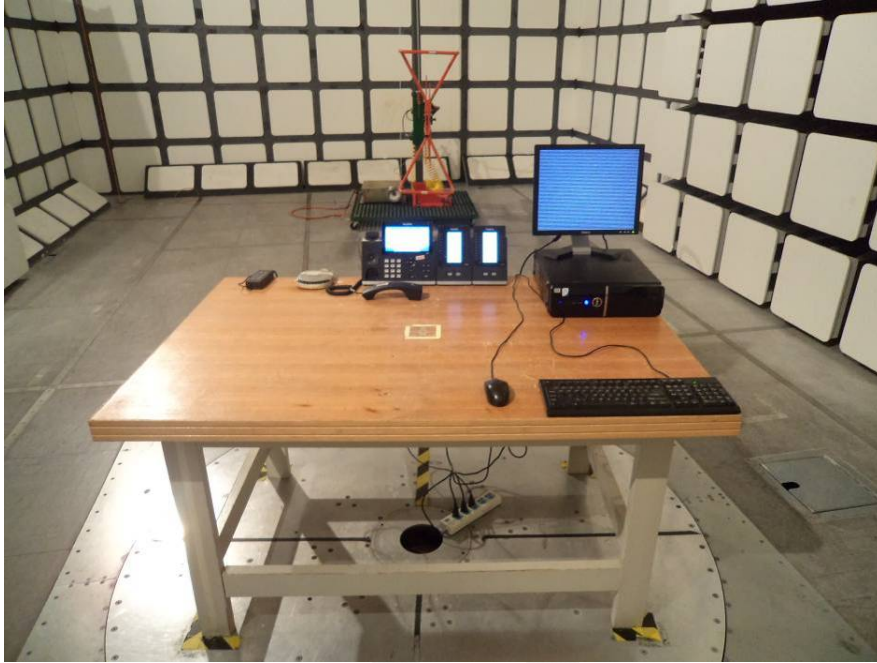
Below 1 GHz: Radiated Disturbance - Front View (Adapter 2 power supply)



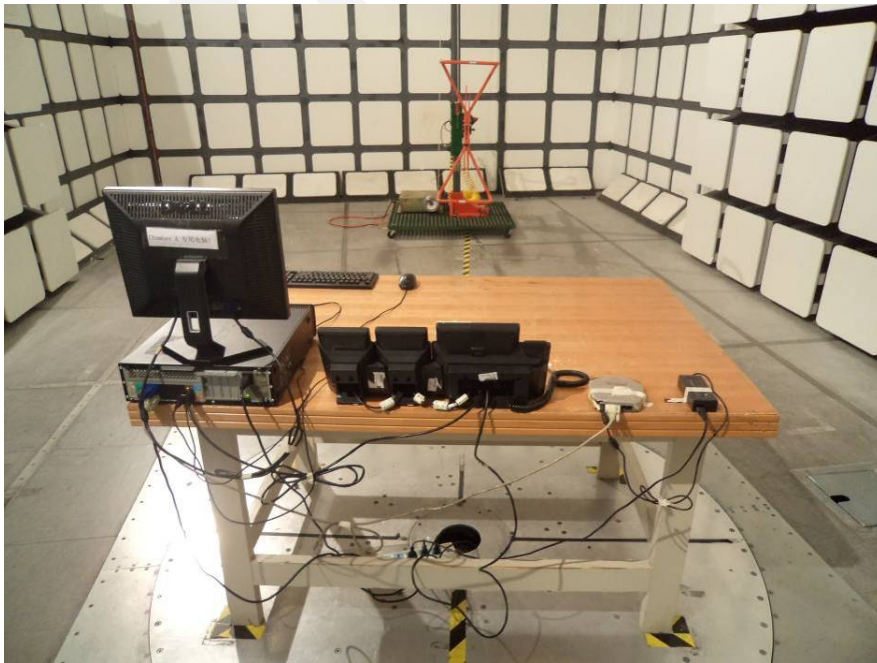
Below 1 GHz: Radiated Disturbance - Rear View (Adapter 2 power supply)



Below 1 GHz: Radiated Disturbance - Front View (PoE power supply)



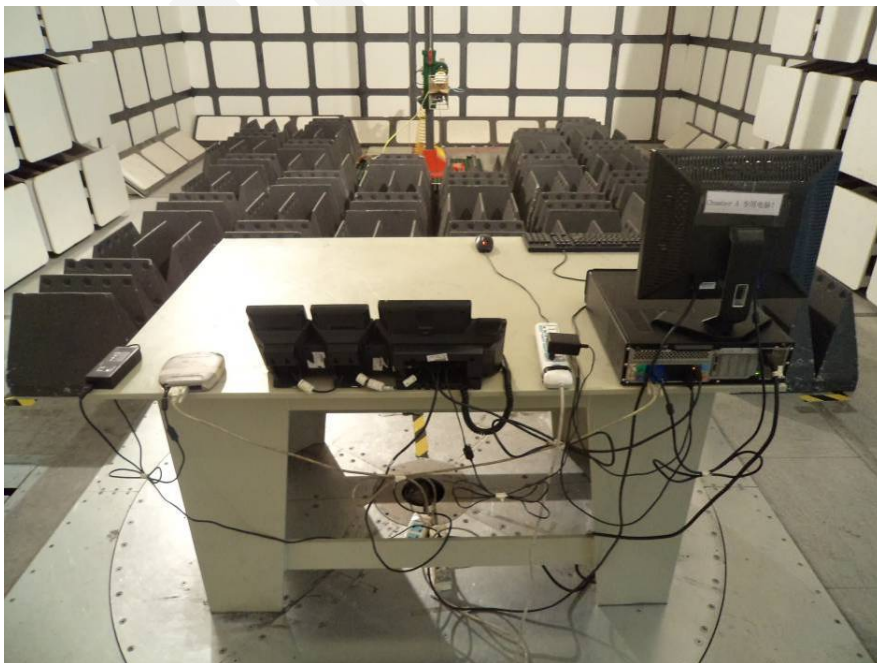
Below 1 GHz: Radiated Disturbance - Rear View (PoE power supply)



Above 1 GHz: Radiated Disturbance - Front View (Adapter 1 power supply)



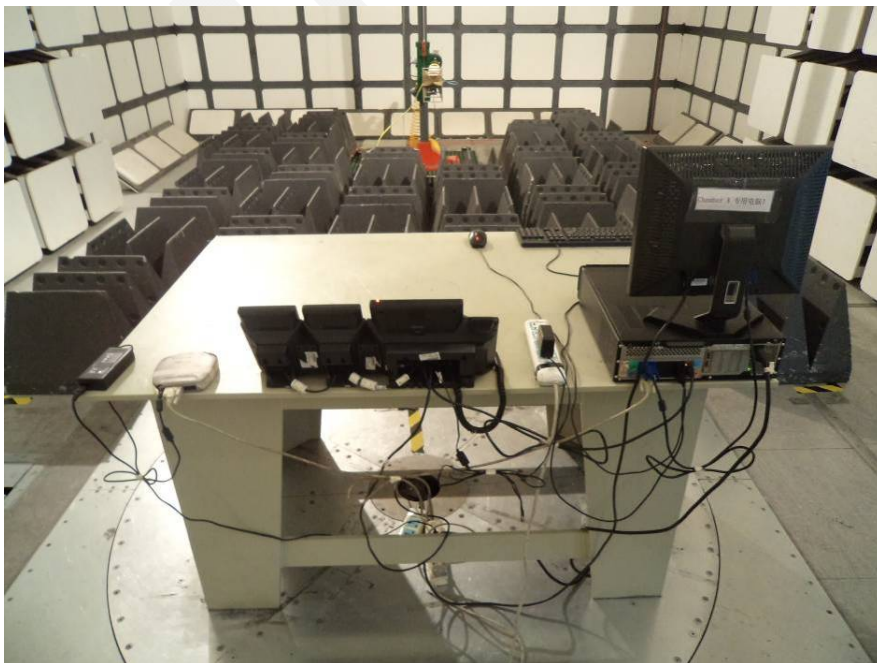
Above 1 GHz: Radiated Disturbance - Rear View (Adapter 1 power supply)



Above 1 GHz: Radiated Disturbance - Front View (Adapter 2 power supply)



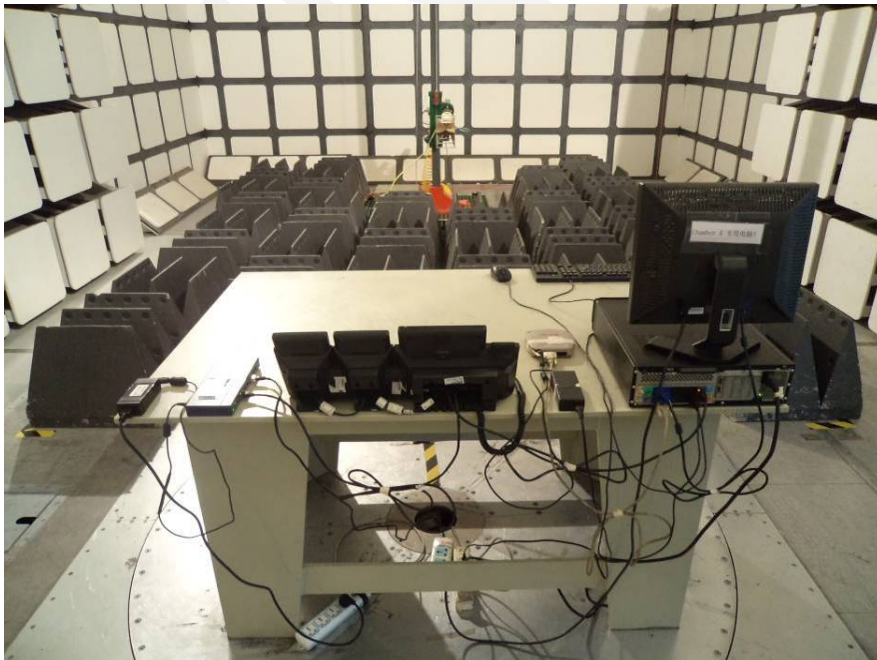
Above 1 GHz: Radiated Disturbance - Rear View (Adapter 2 power supply)



Above 1 GHz: Radiated Disturbance - Front View (PoE power supply)



Above 1 GHz: Radiated Disturbance - Rear View (PoE power supply)



******* END OF REPORT *******